

Sr out-diffusion and spatially mapped Co valence for operational LSCF cathodes

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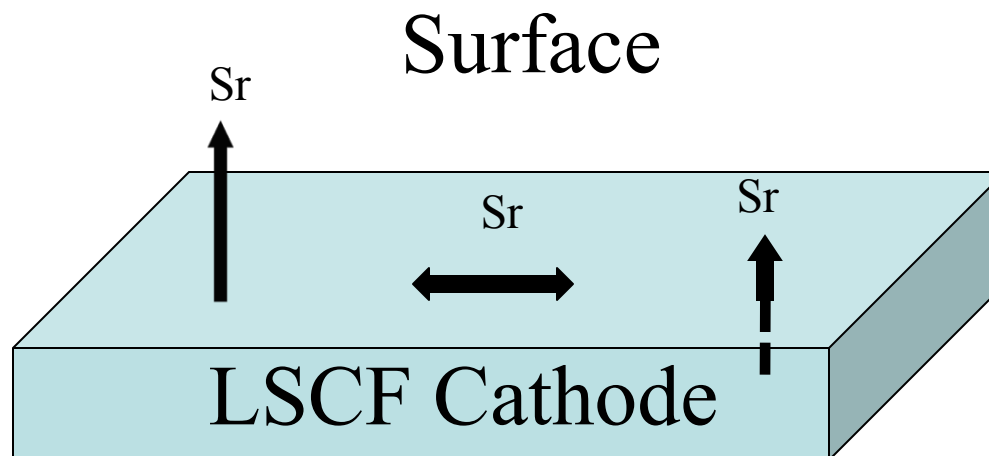


Research Thrusts

1. Directed SOFC materials development thru rapid X-ray characterization.
2. Identification of interfacial barriers to oxygen ion formation and diffusion.
3. X-ray characterization under operational conditions.



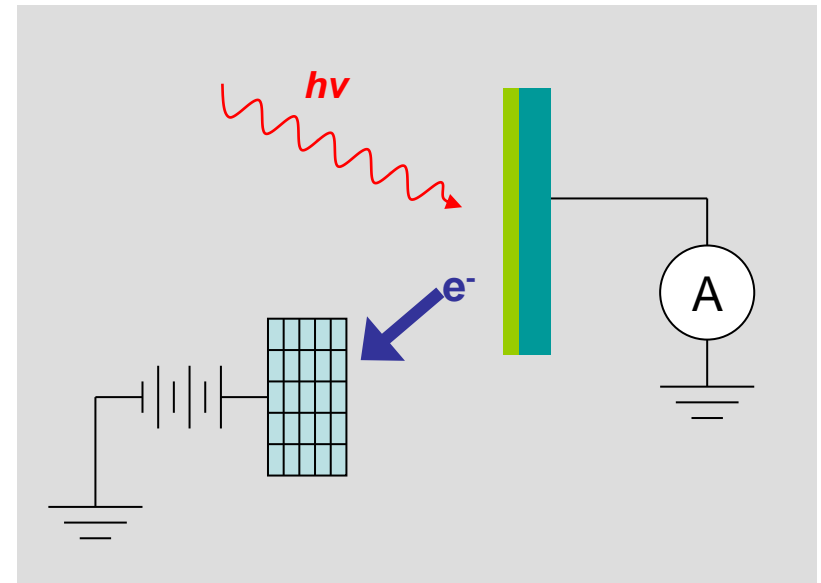
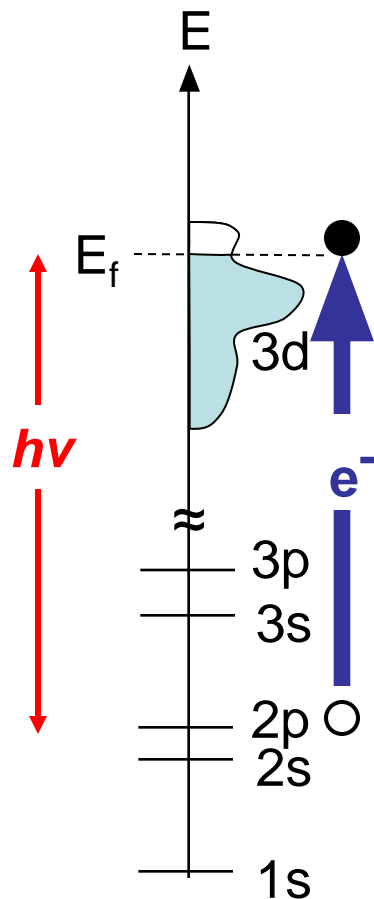
Example – Map Sr out-diffusion



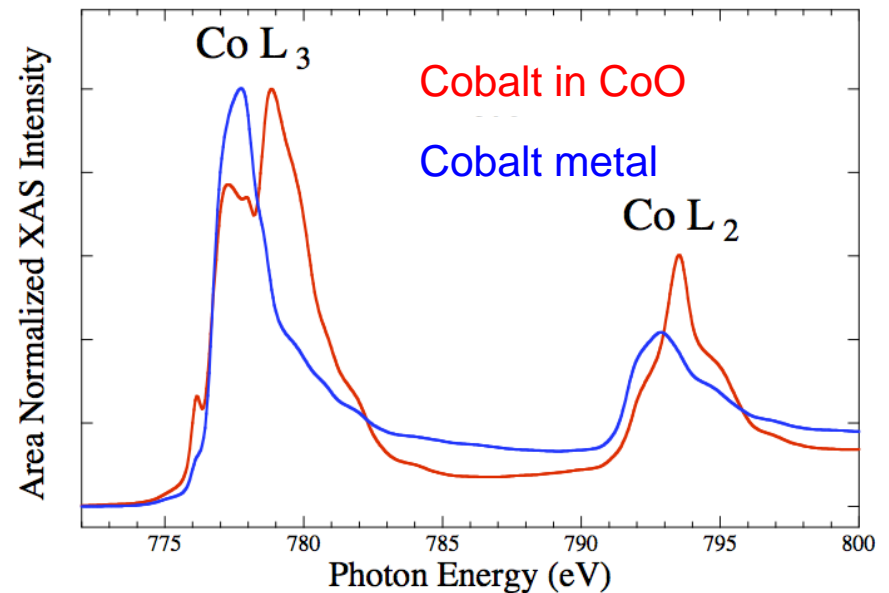
How do operational conditions
affect Sr mobility?



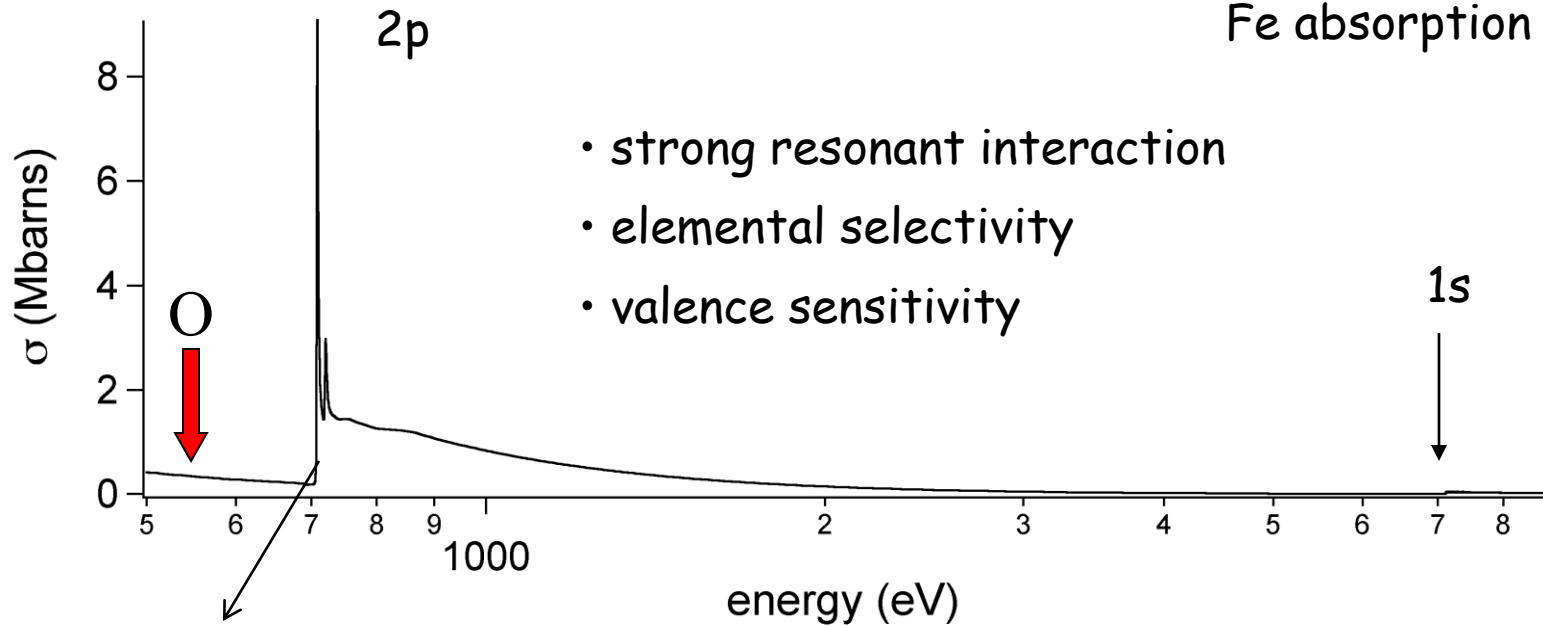
X-ray Absorption Spectroscopy (XAS)



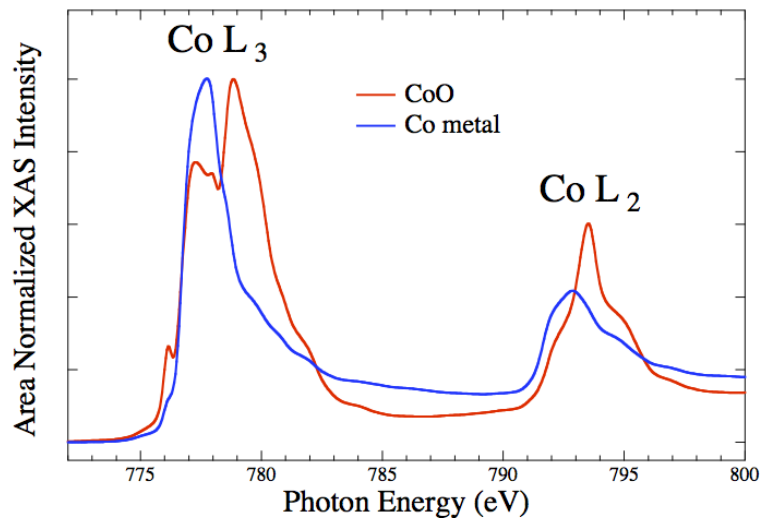
Co L edge XAS



Soft x-rays are ideal for buried interfaces!



Co L edge XAS



spatially map elemental
valence at buried interfaces
under operational conditions

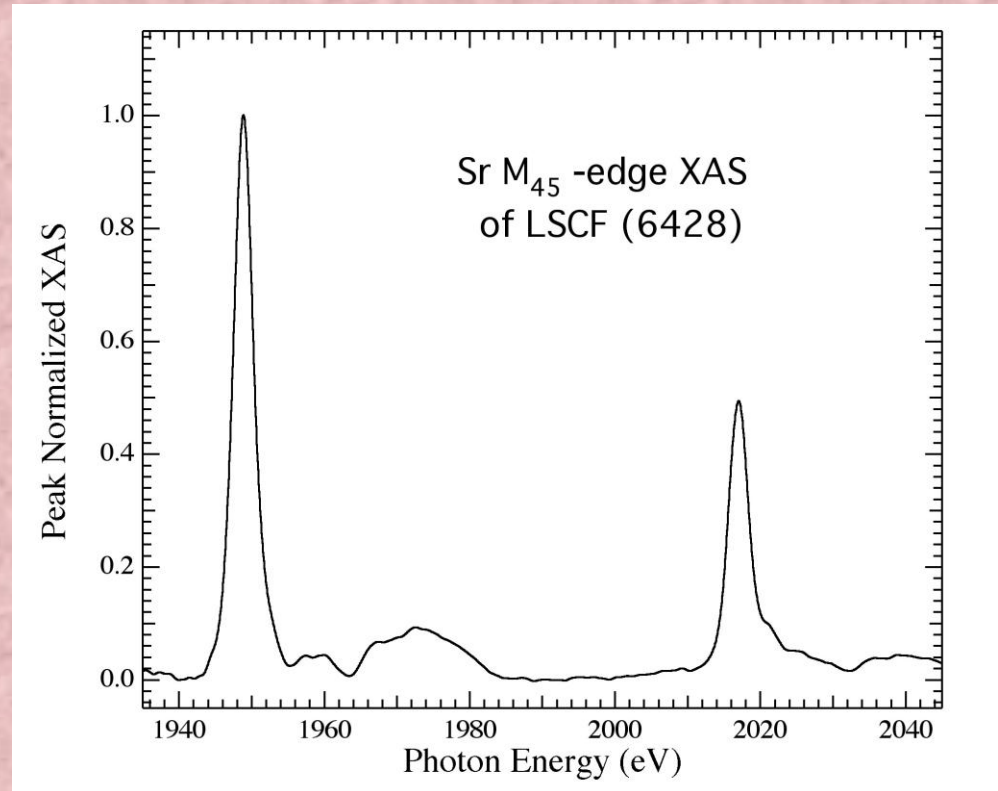
Example – Map Sr out-diffusion

Two problems

Sr is both on the surface and in bulk.

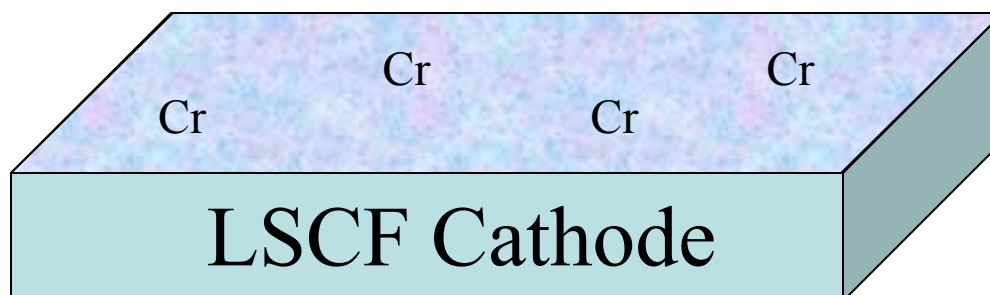
Sr remains as Sr^{2+} !

No change



Solution – Elemental tagging

Introduce surface Cr



Cr present as Cr_2O_3 (Cr^{3+})

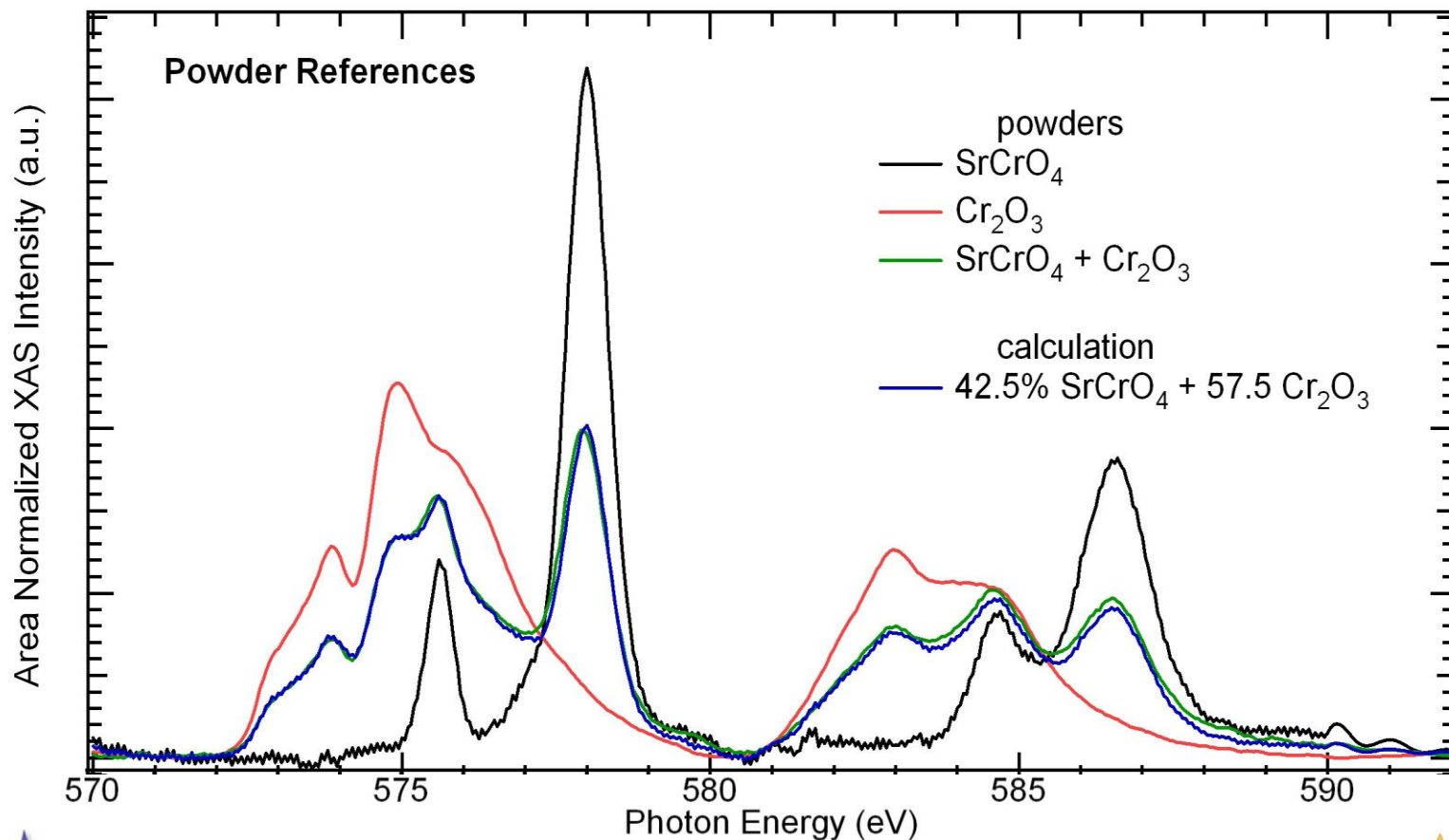
or

(in the presence of SrO) as SrCrO_4 (Cr^{6+})



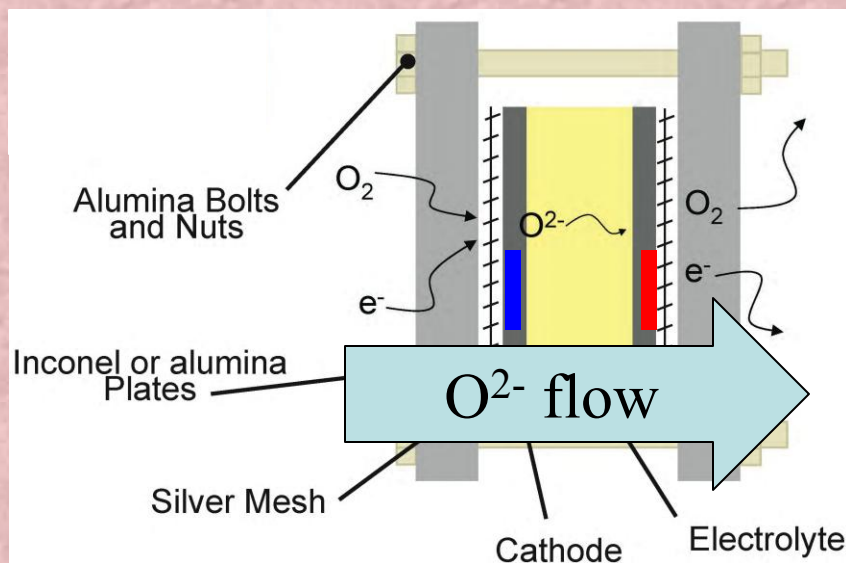
EXAMPLE – Sr out-diffusion

Sr modifies Cr valence!

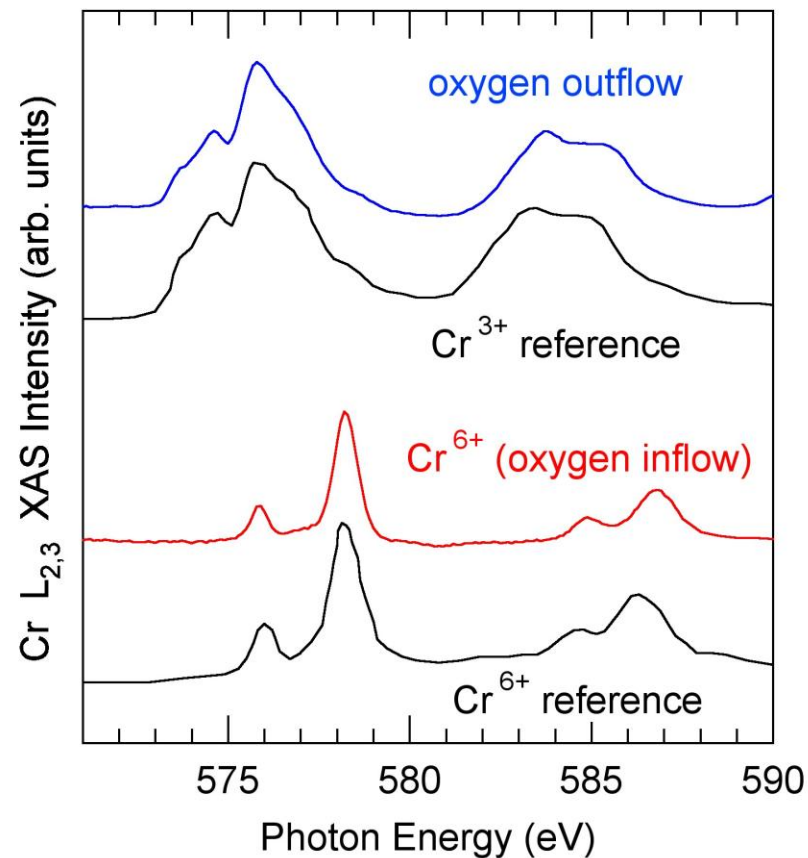


Oxygen ion flow direction modifies Cr valence!

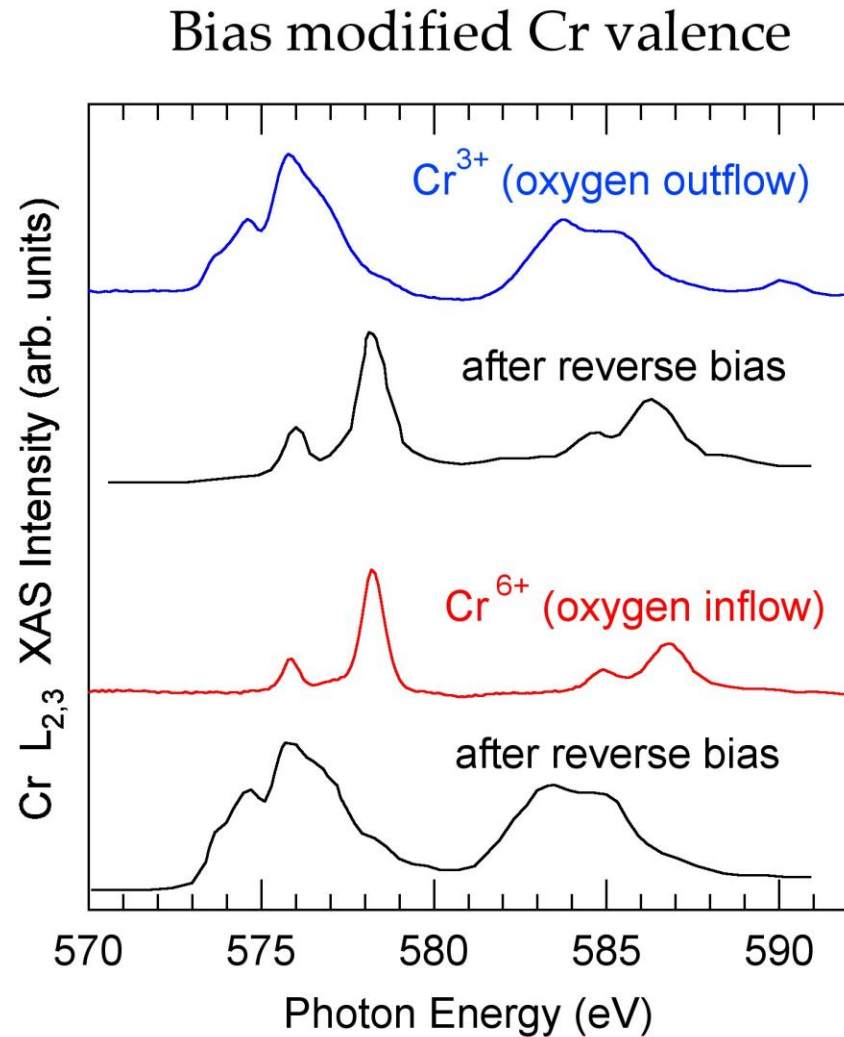
Bias driven symmetric cell
(2 half cells)



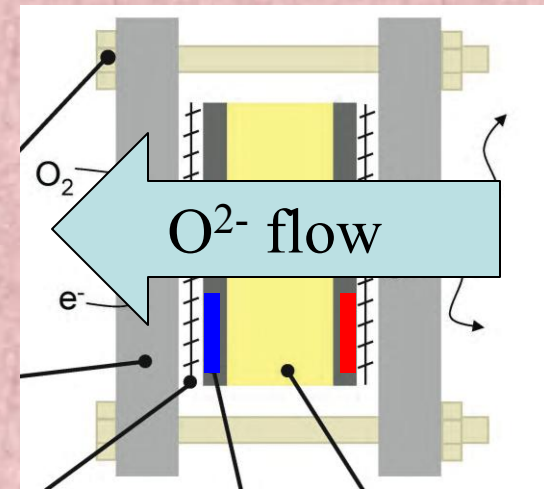
Ion flow modified Cr valence



Oxygen ion flow (*and bias*)

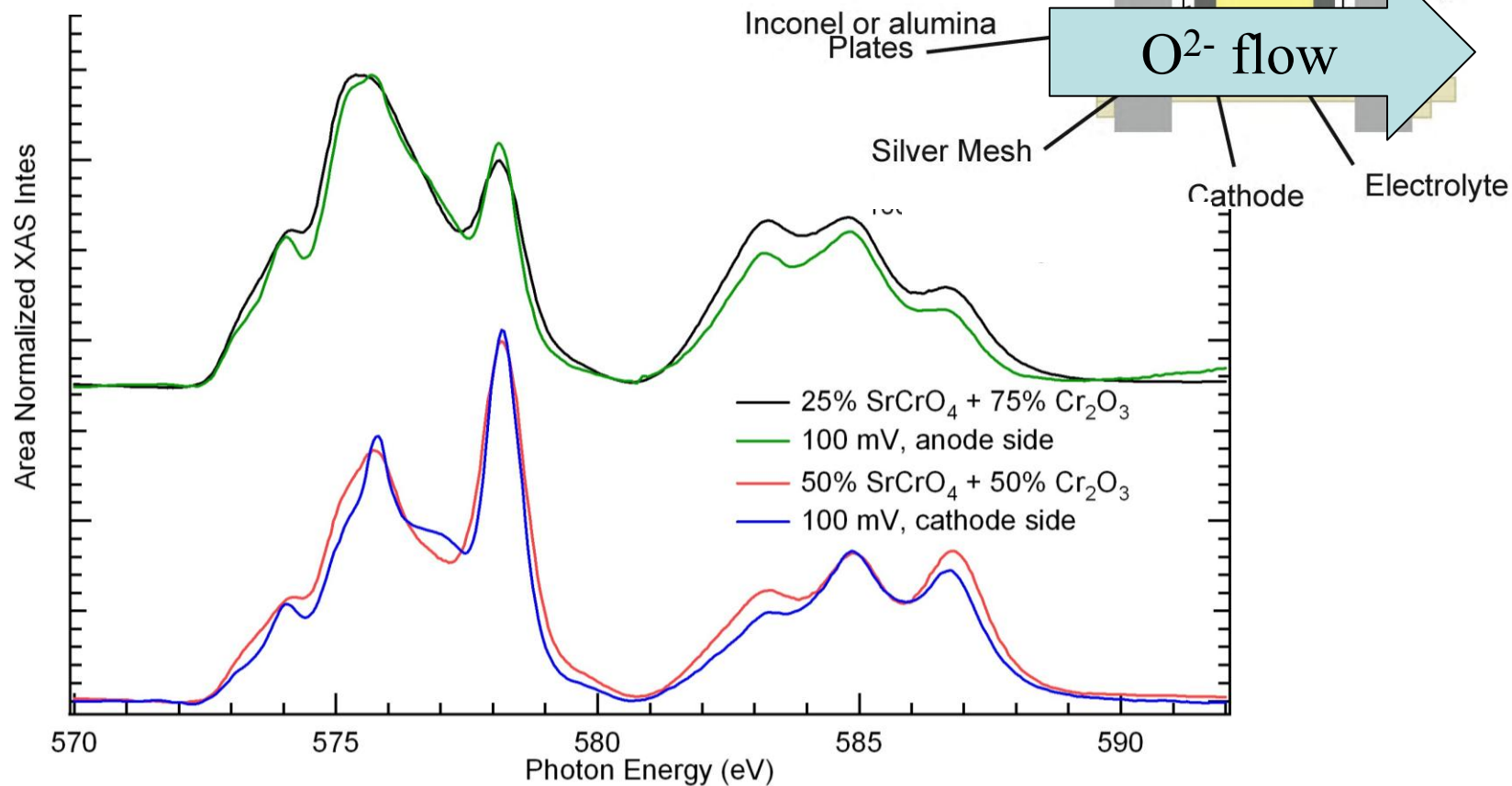


reverse bias



Oxygen ion flow
reverses Cr valence!

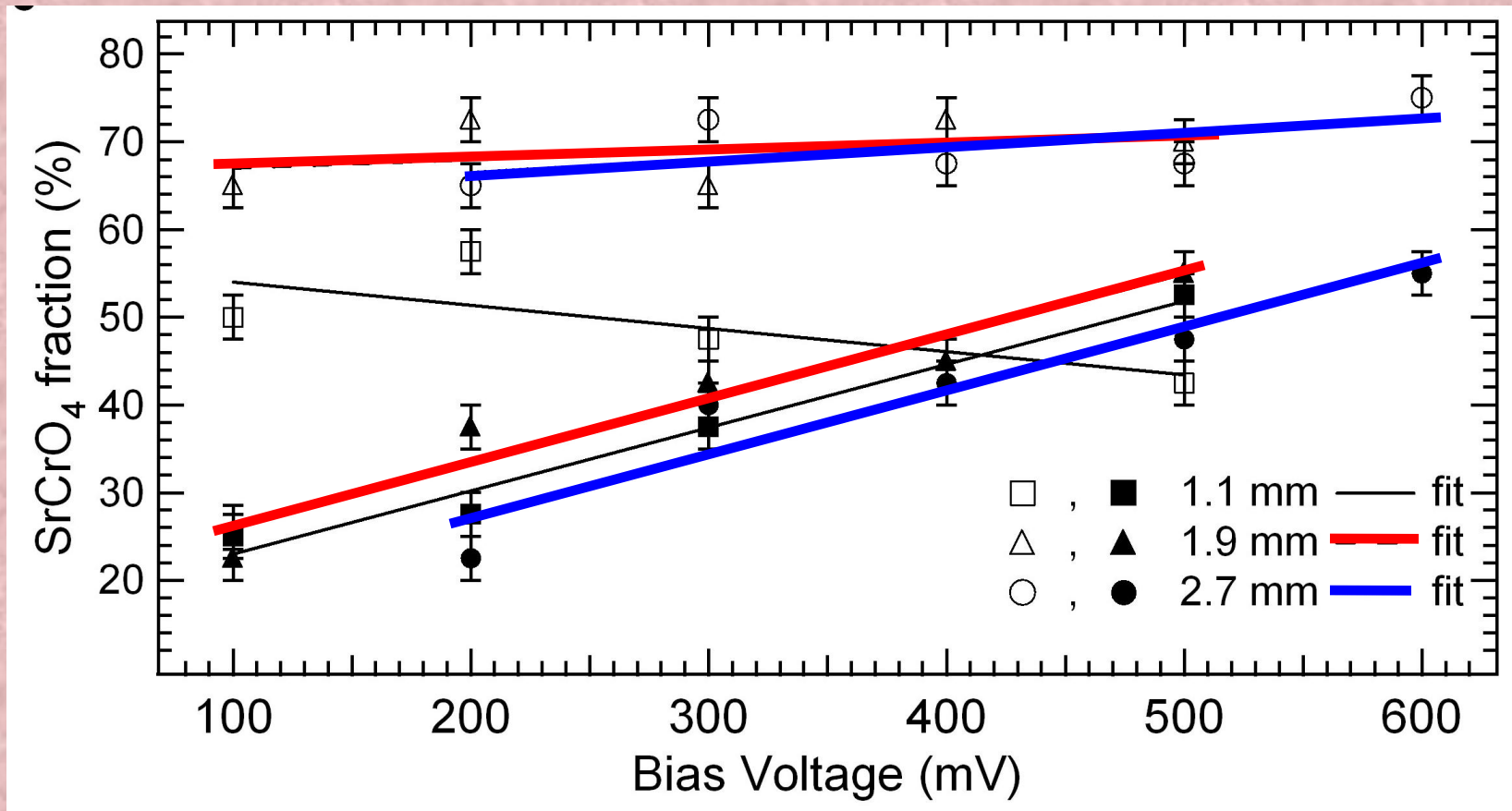
1.1 mm electrolyte
850 °C 100 mV



Electrochemical Environment

solid – anode

empty - cathode



Bias driven Sr out-diffusion (V^{O2-})



PLD samples (symmetric depositions)

- Substrate 0.5 mm single crystal YSZ (polished)
- Sintered GDC and LSCF targets
- 2 types of samples:

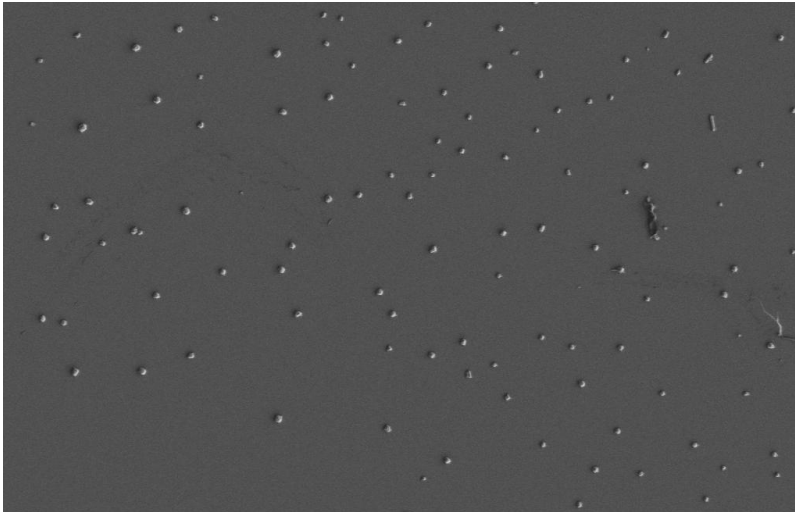
LSCF/YSZ/LSCF

LSCF/GDC/YSZ/GDC/LSCF

- Thickness: LSCF = 10 nm; GDC = 20 nm
- GDC interlayer to prevent secondary phase formation

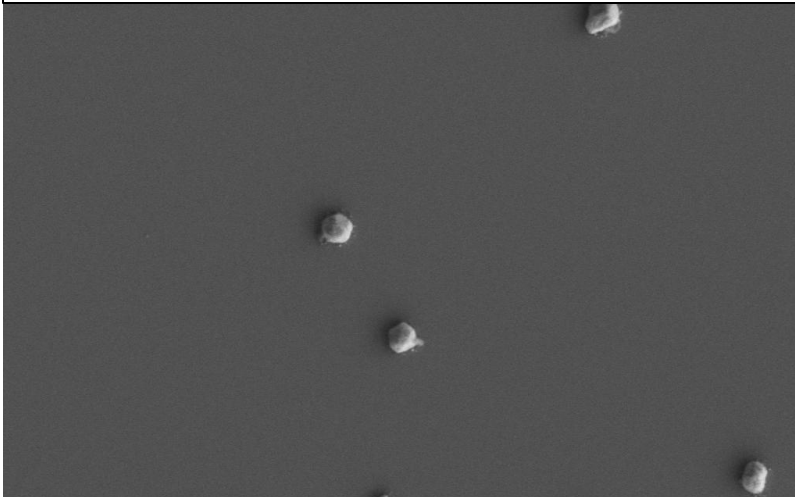
SEM Sr segregation

Pulse laser deposited LSCF/GDC



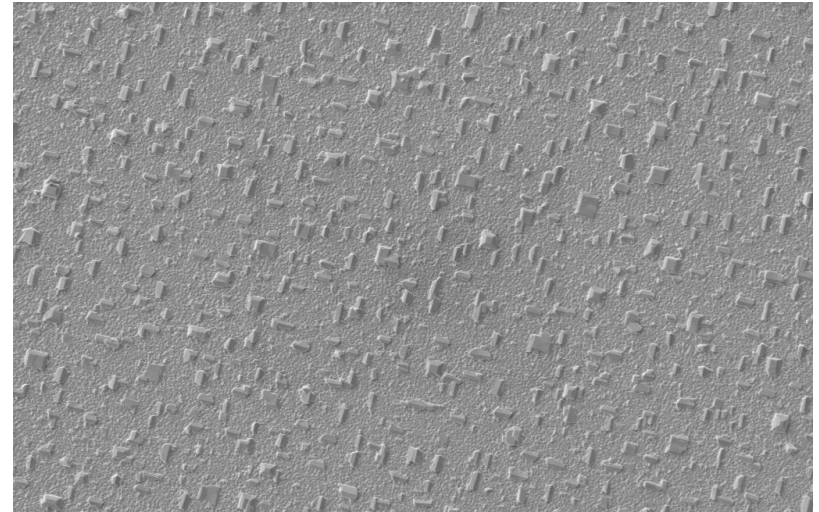
2 μm

As grown



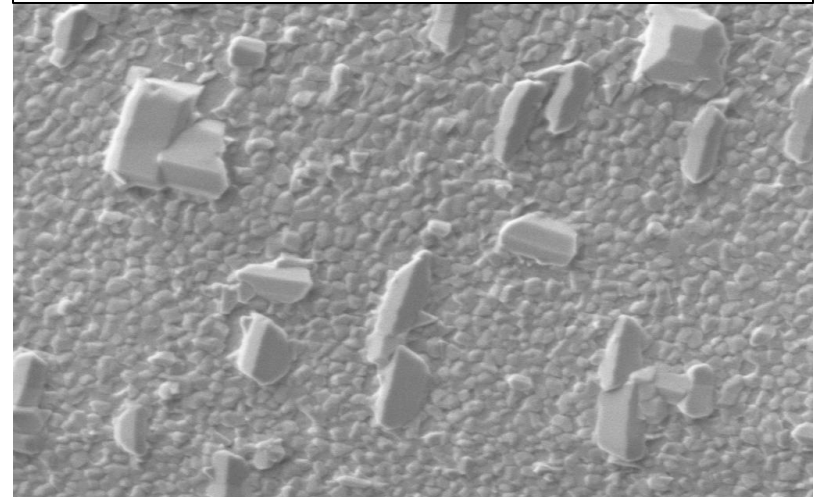
1 μm

particulates



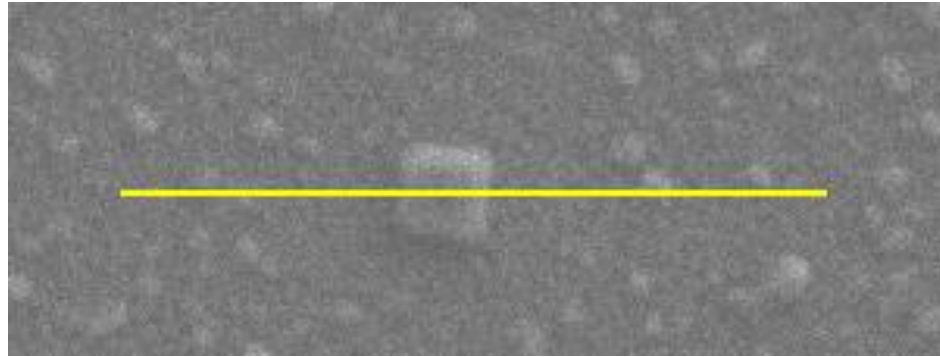
2 μm

100 hr 800 °C 500 mV



1 μm

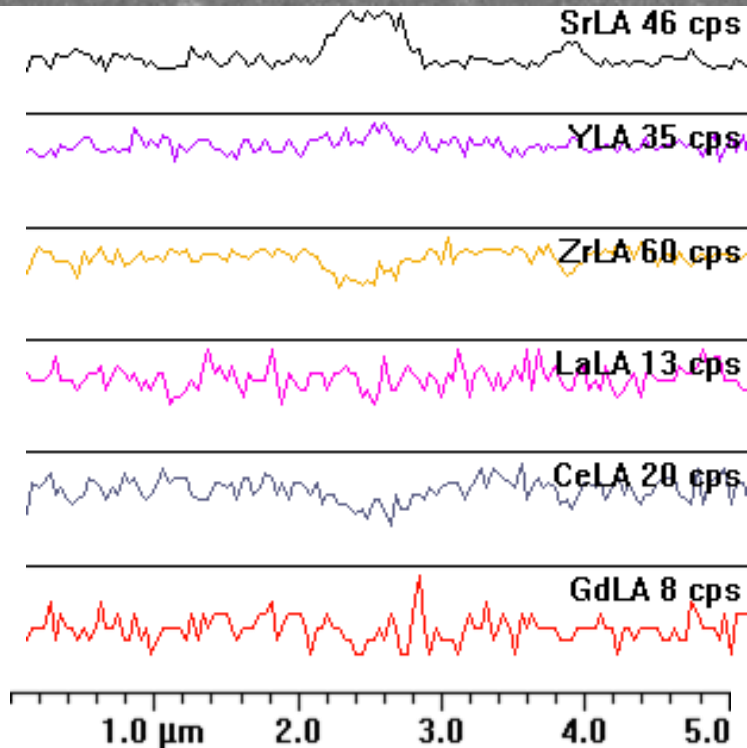
crystallites



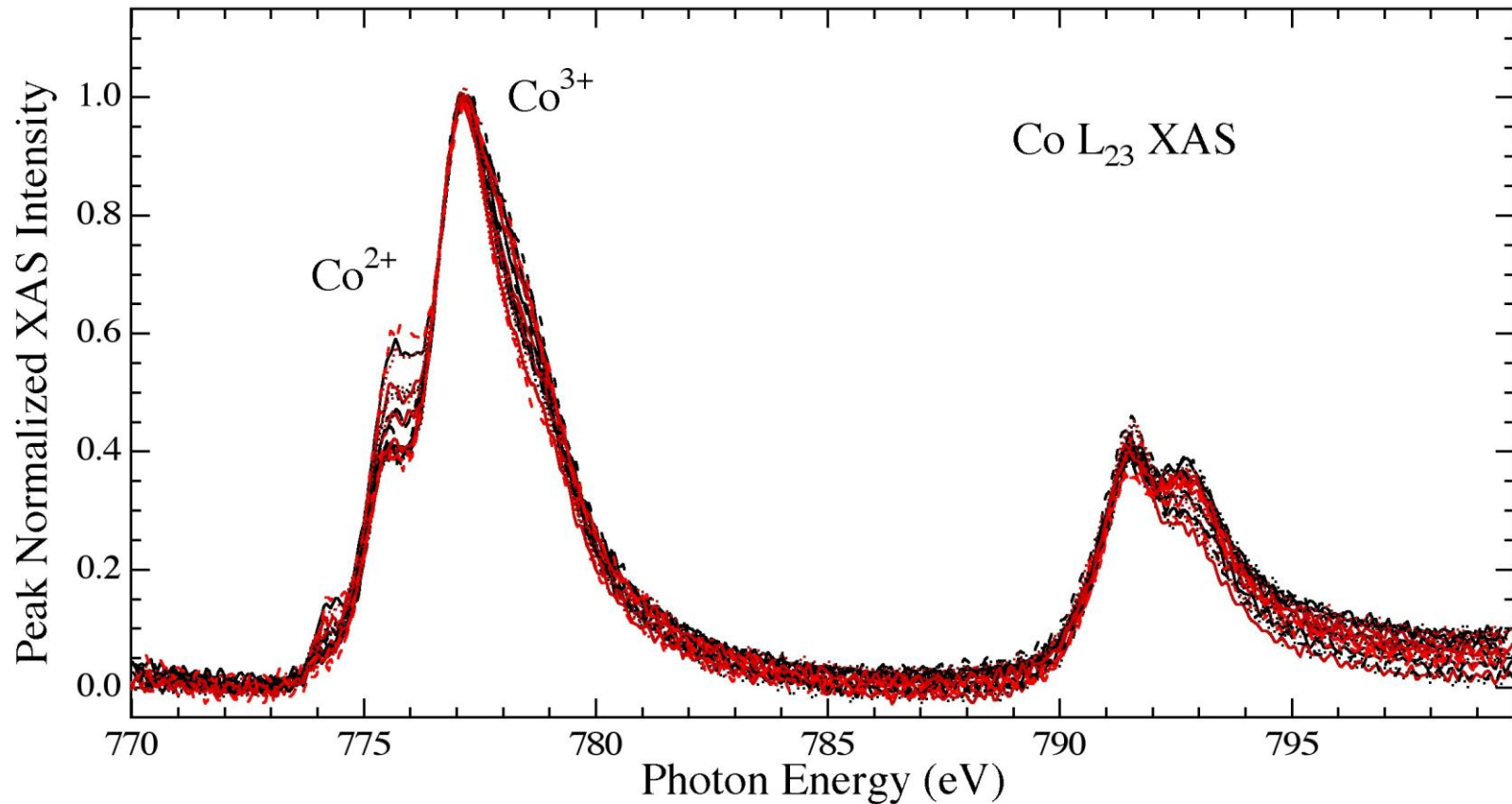
EDS line-scans

- Line-scan shows *increase* in Sr
- Reduction in Zr and Ce
- XPS shows Sr present as SrO and LSCF

→ Surface segregated Sr

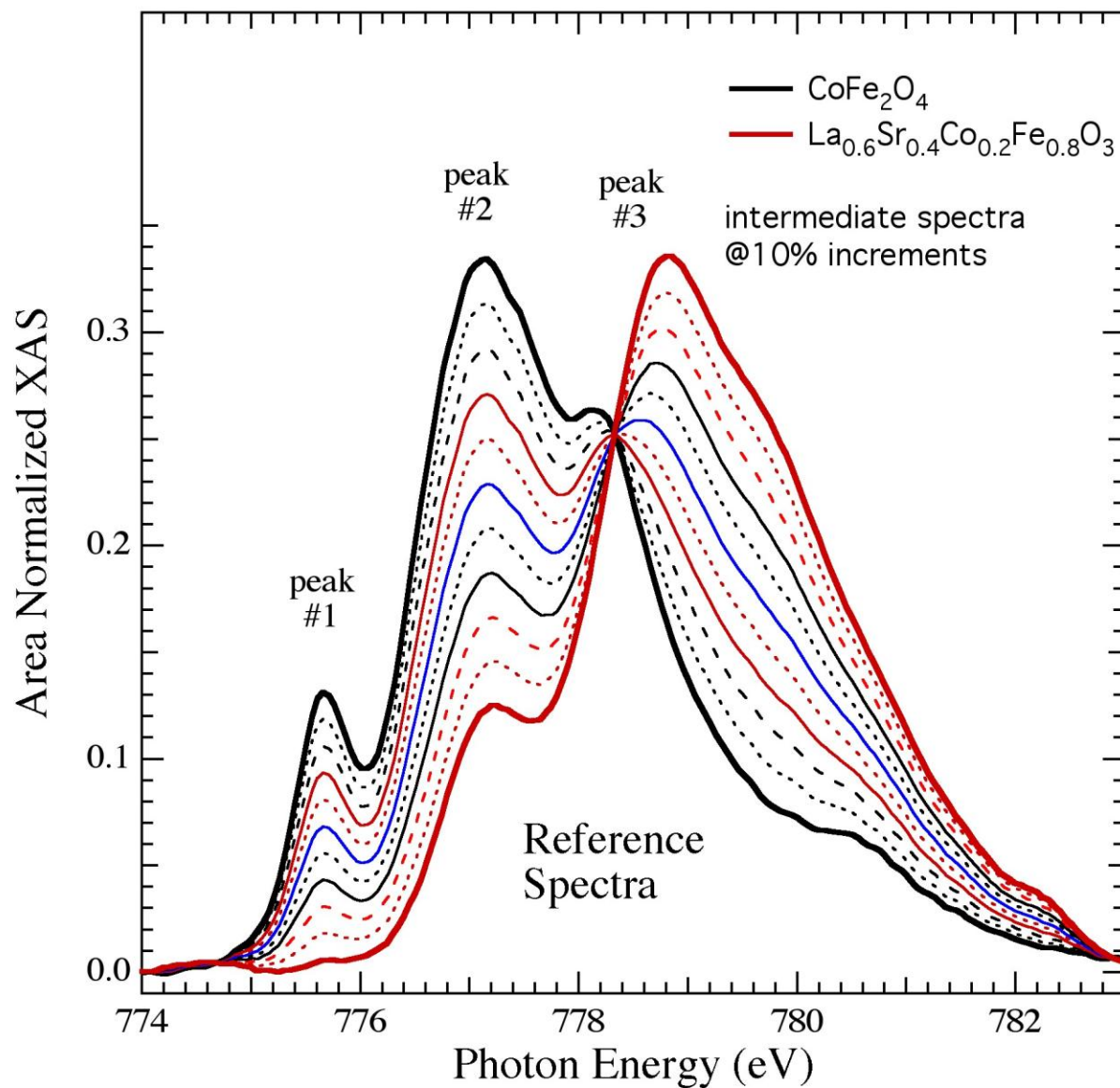


Co valence shift from Sr segregation



Removing Sr also increases Co³⁺ and decreases Co²⁺ concentrations

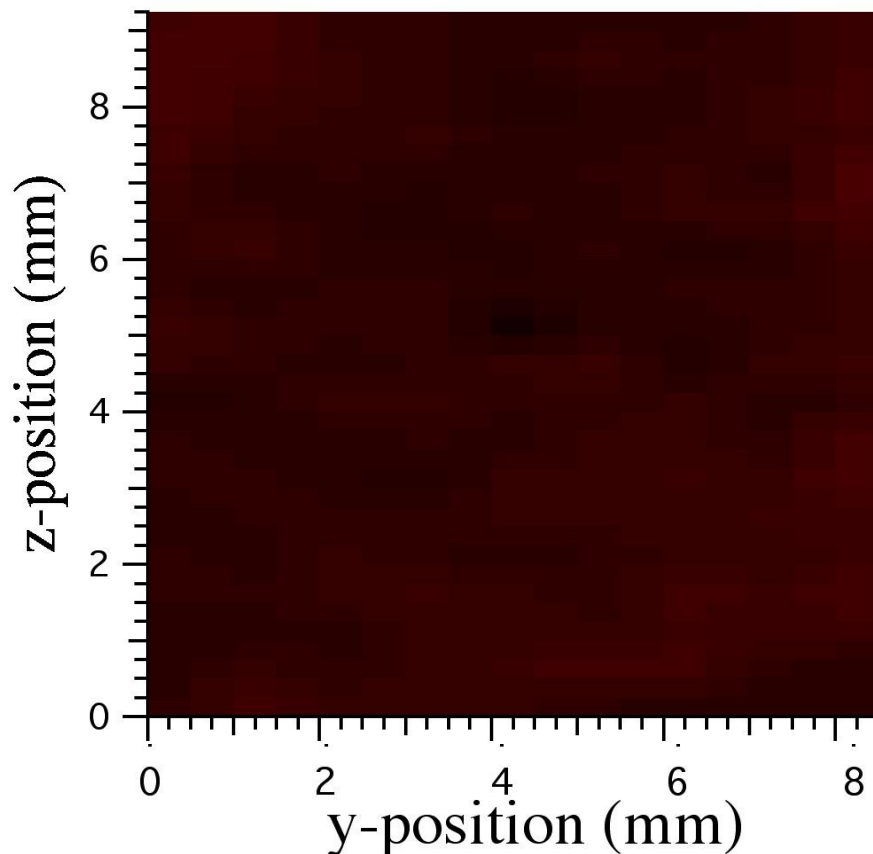
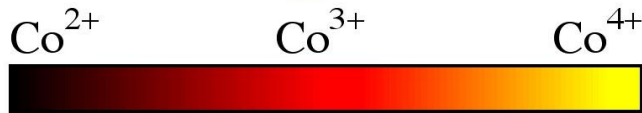
Measure of surface Sr



Co L₃-edge
valence
reference
spectra

Co valence map

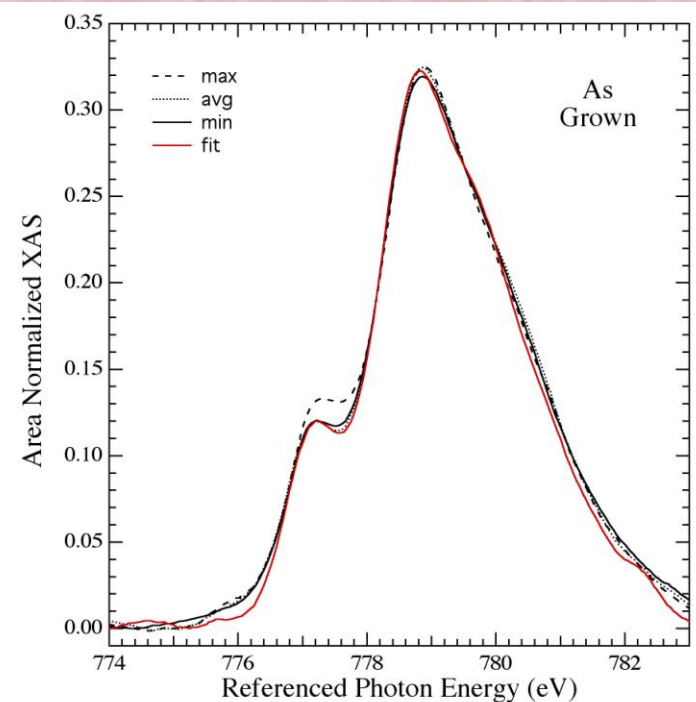
As-grown



Co present as Co^{2+}
(10% variation)

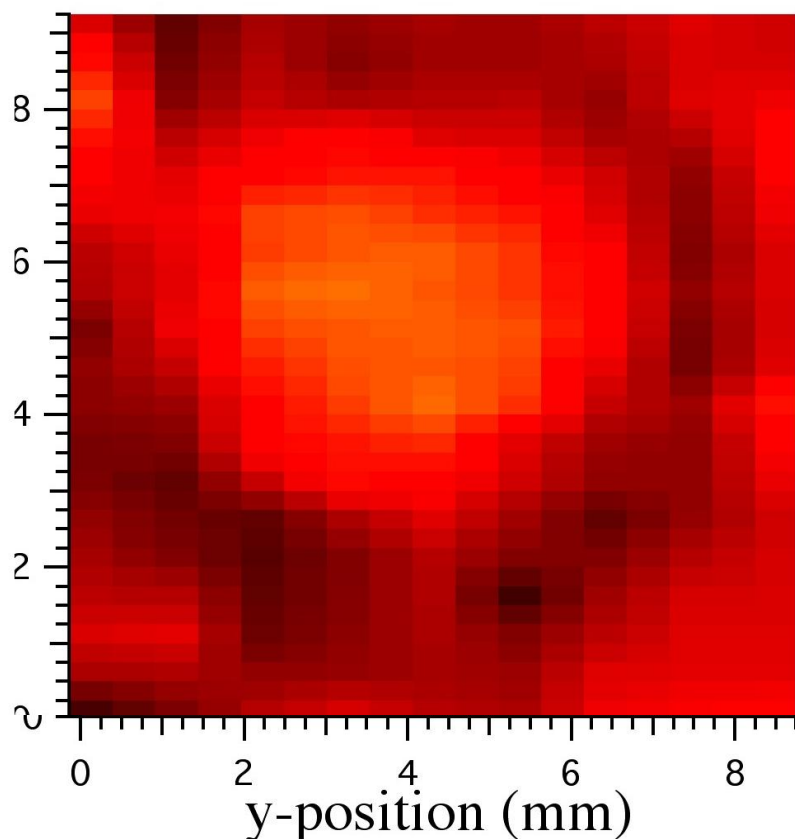
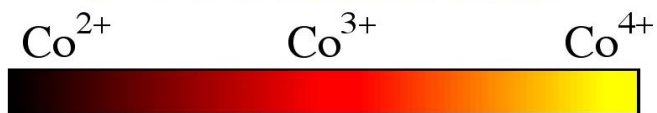
LSCF oxygen deficient
(PLD vacuum cool down)

Reproduced with
vacuum anneal



Co valence map

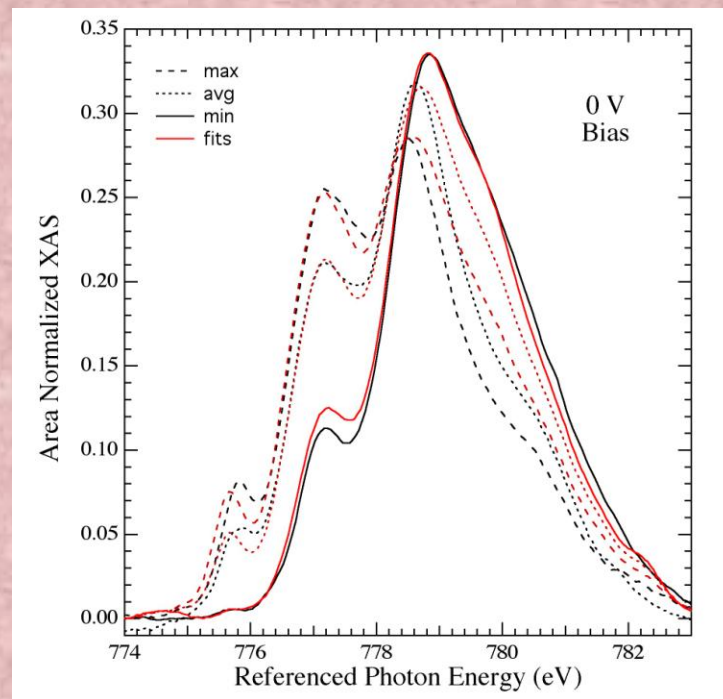
0 V Potential bias



Air anneal @ 850 °C

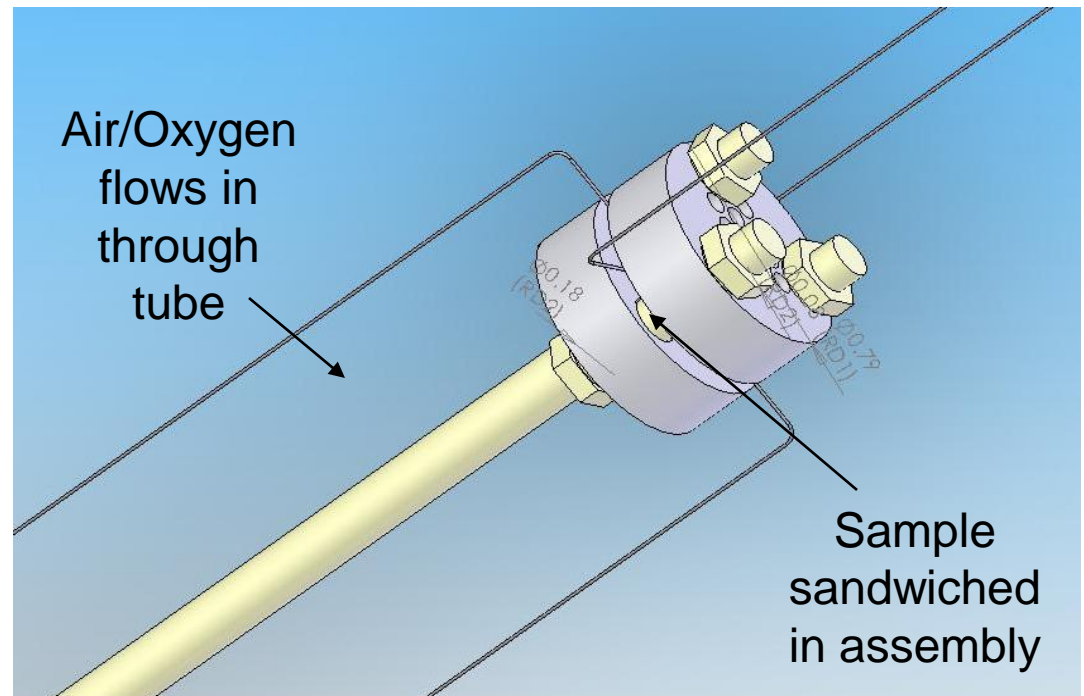
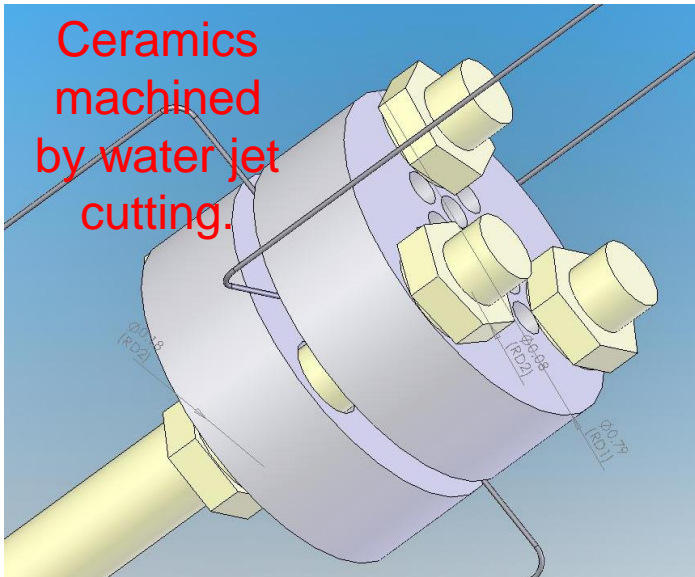
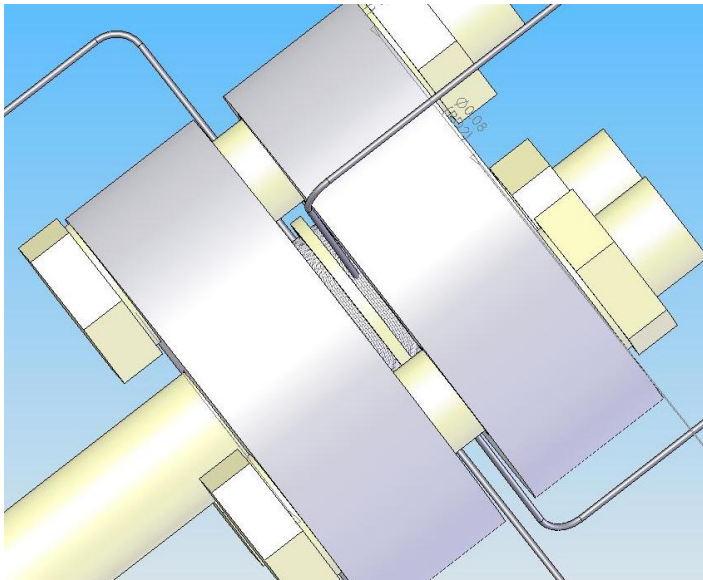
Co present as Co^{3+}
(40% variation)

Circular pattern

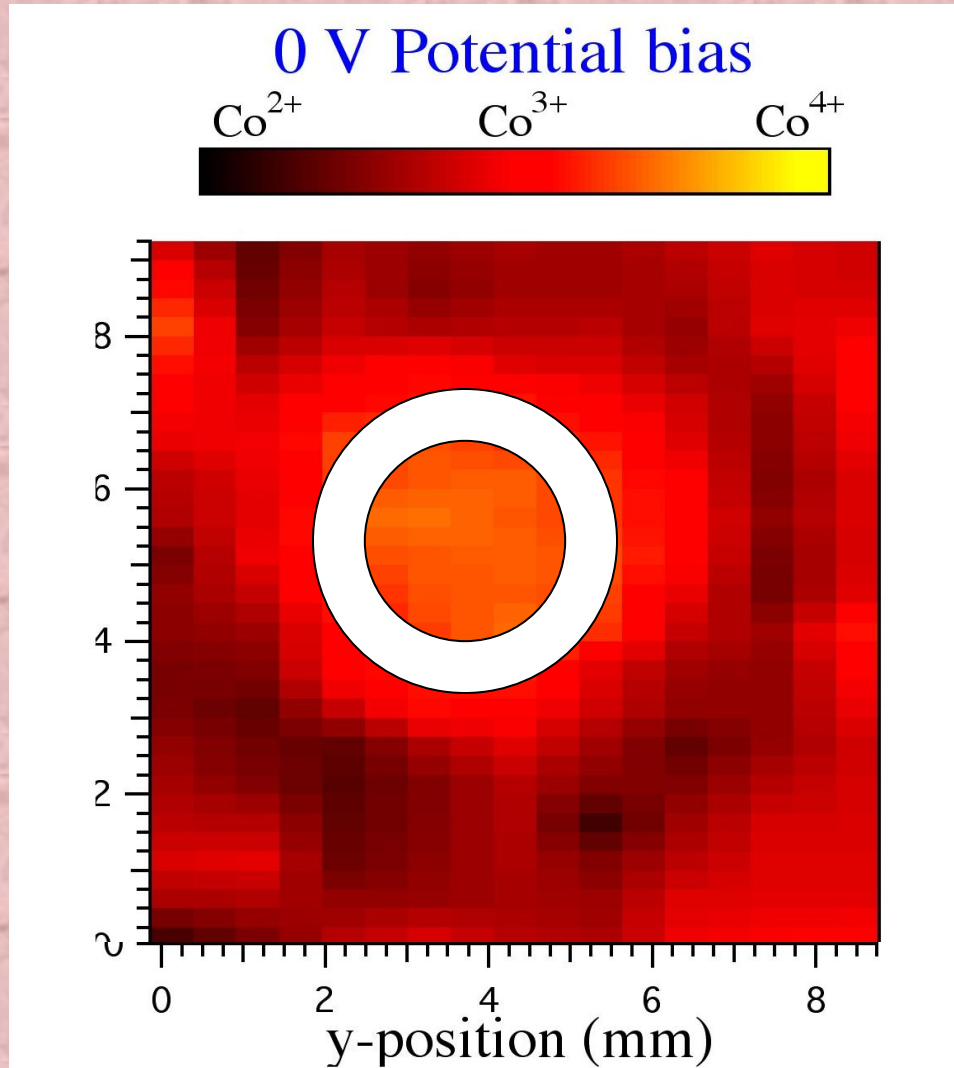


Electrical Potential Testing Rig

- Entire ceramic and gold assembly is inserted into tube furnace.
- Symmetric SOFC half cells



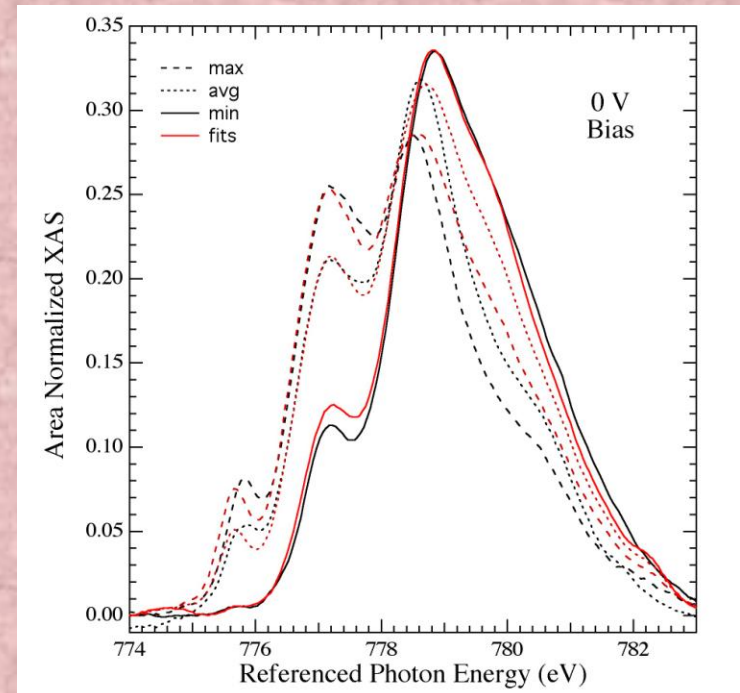
Co valence map



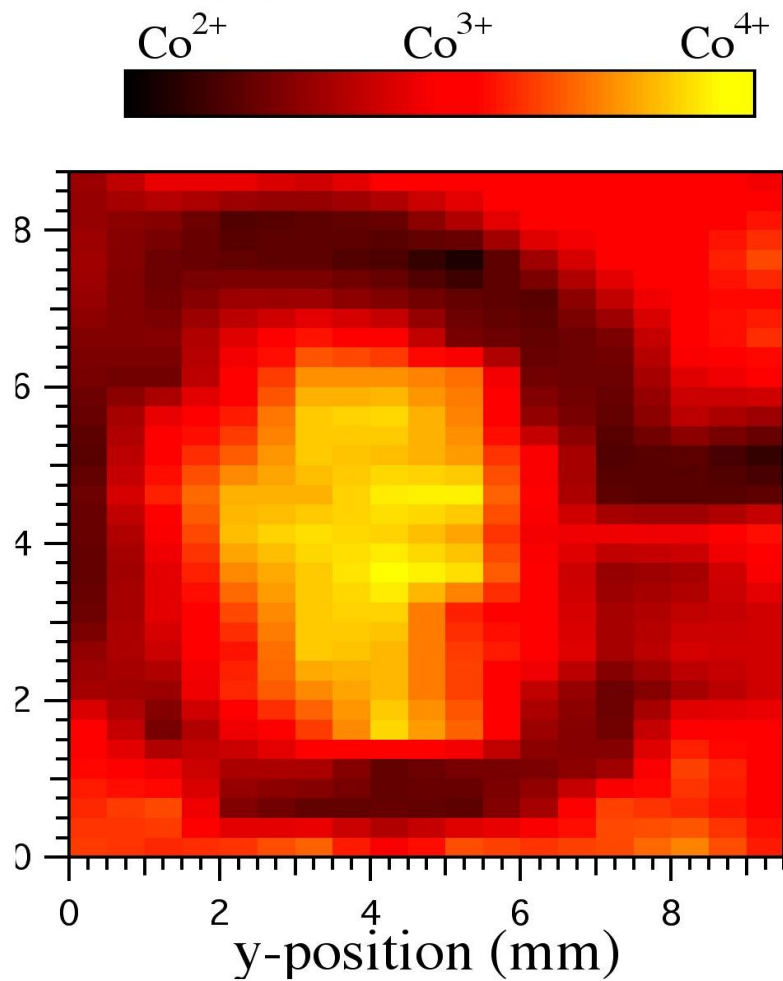
Co present as Co³⁺
(40% variation)

Circular pattern

Matches air inlet



Co valence map

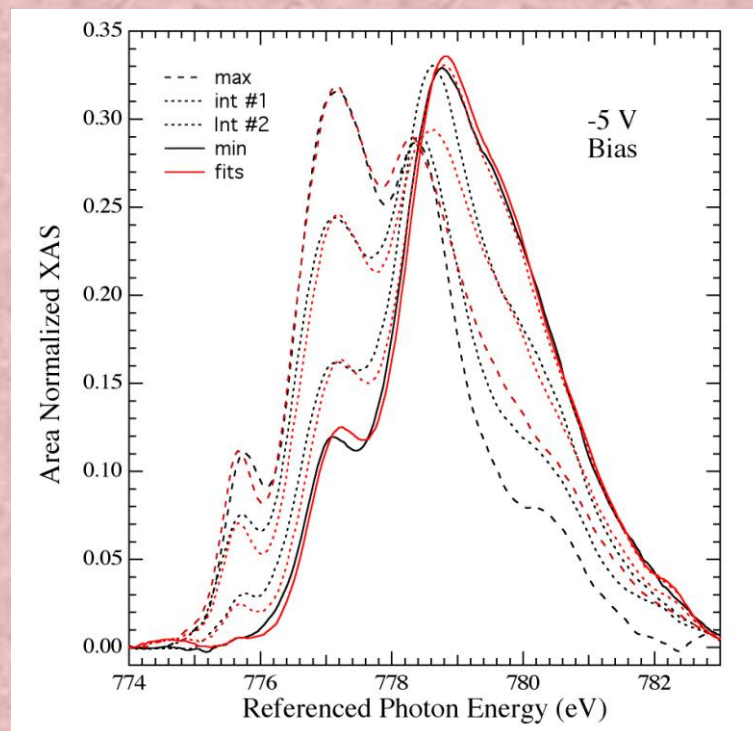


-500 mV Potential bias

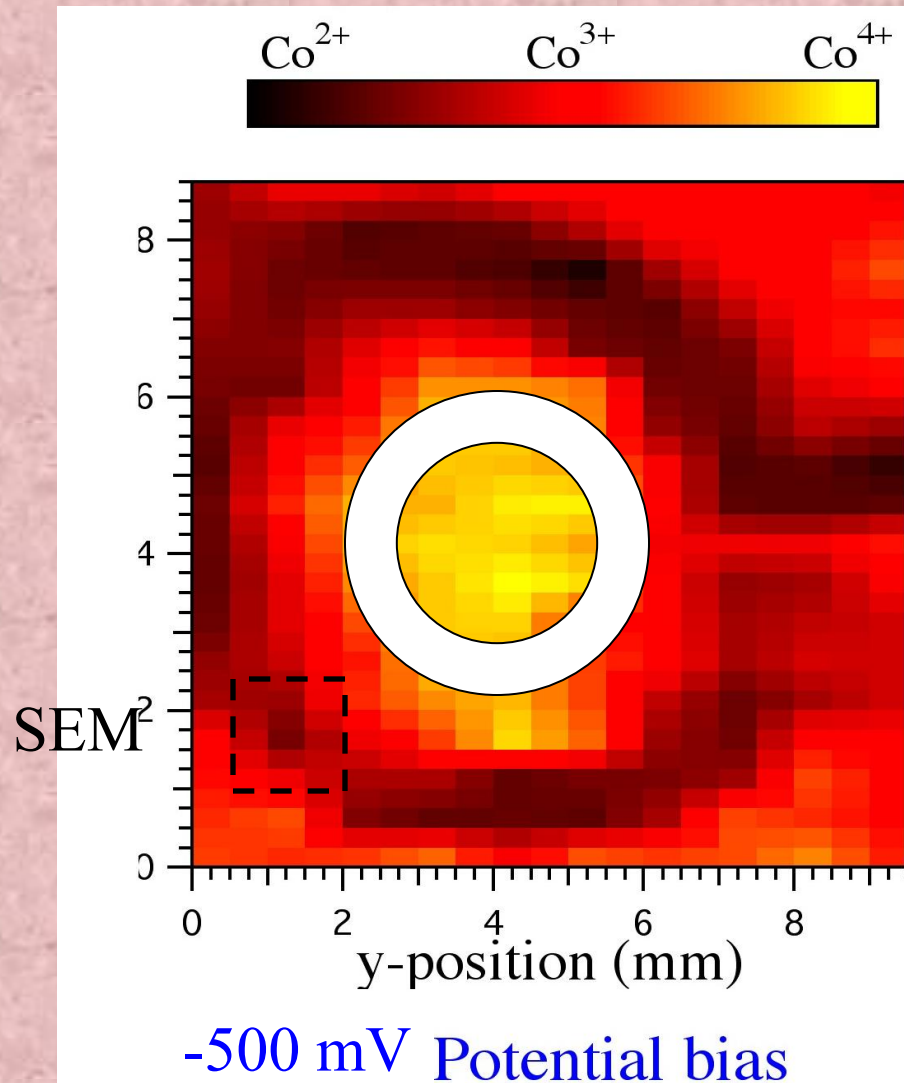
Co present as Co³⁺ and Co⁴⁺
(130% variation)

Circular pattern

Matches air inlet



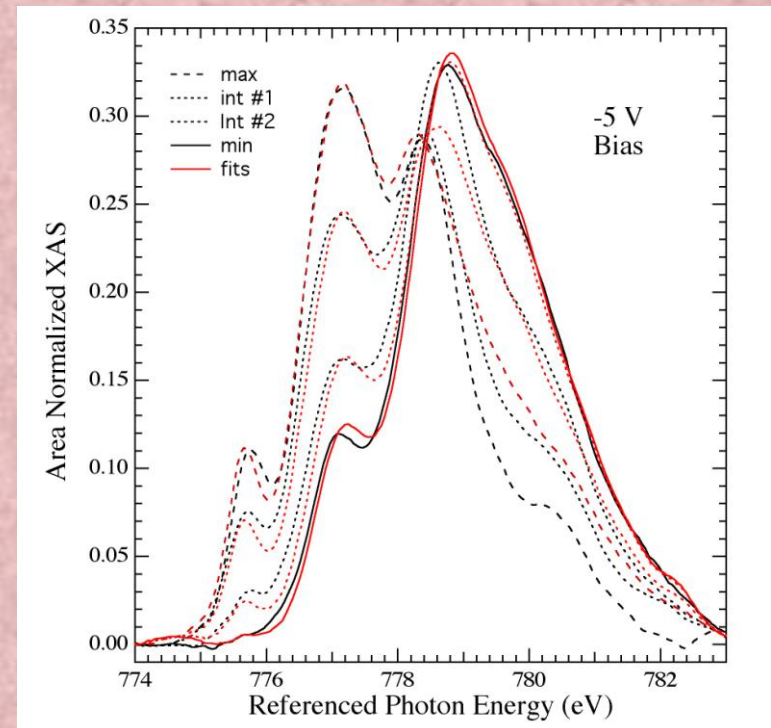
Co valence map



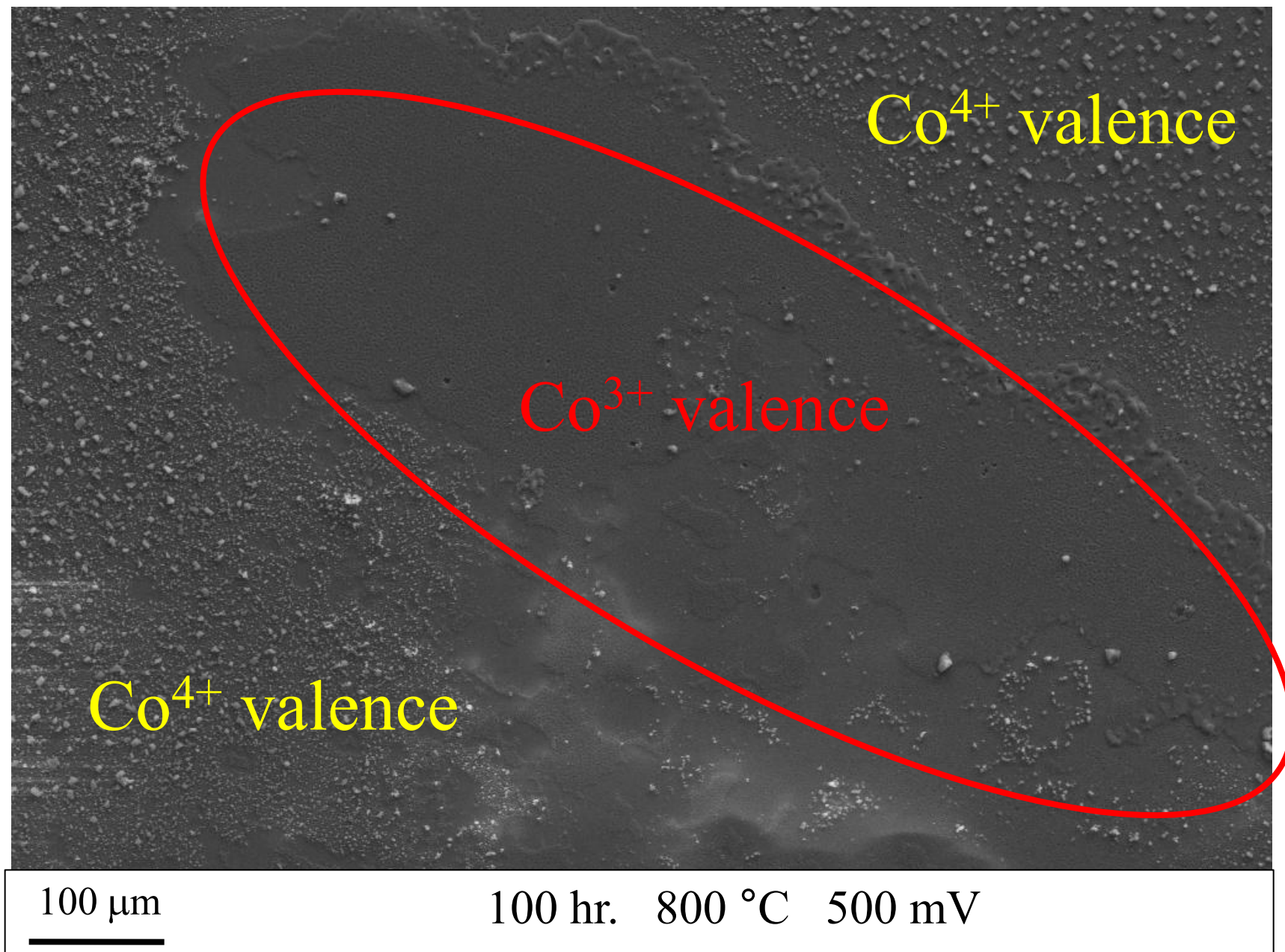
Co present as Co³⁺ and Co⁴⁺
(130% variation)

Circular pattern

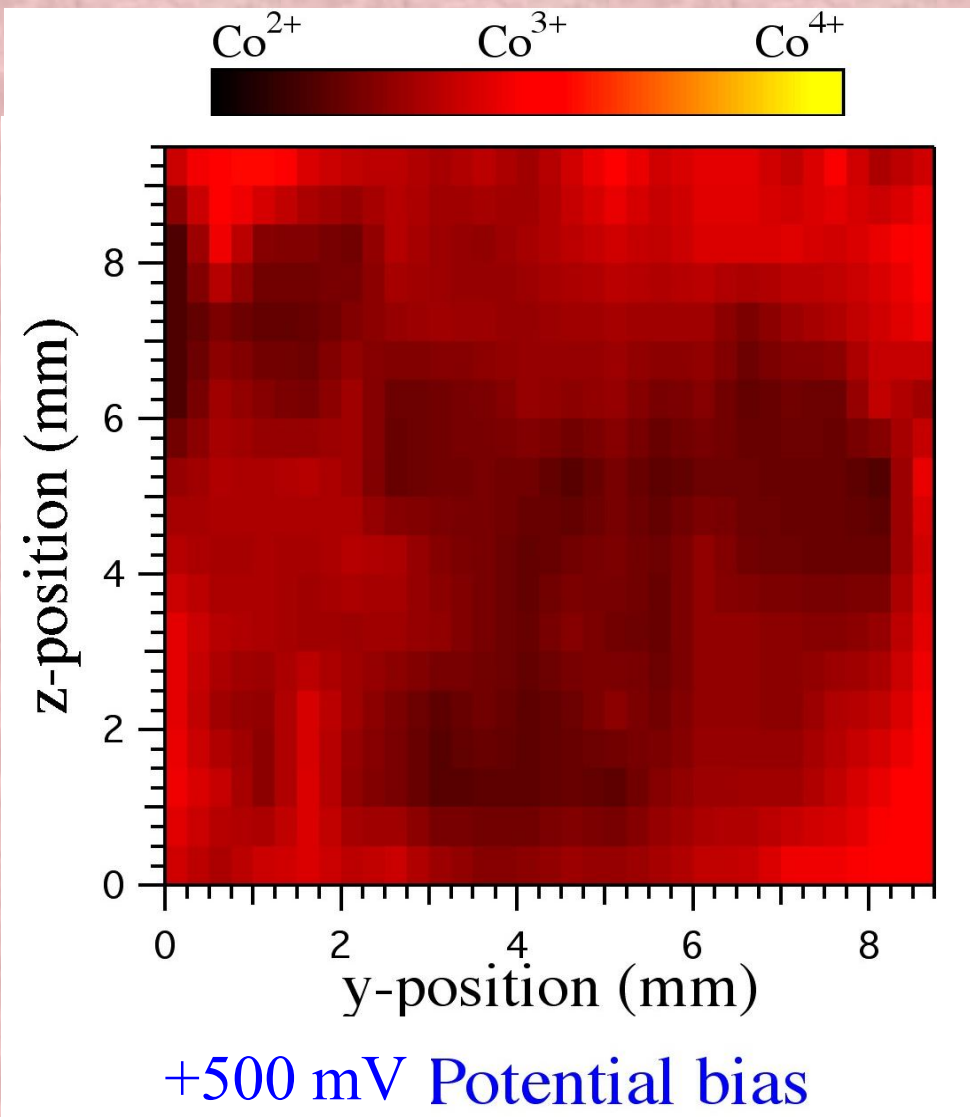
Matches air inlet



SrO formation correlated to Co^{4+}

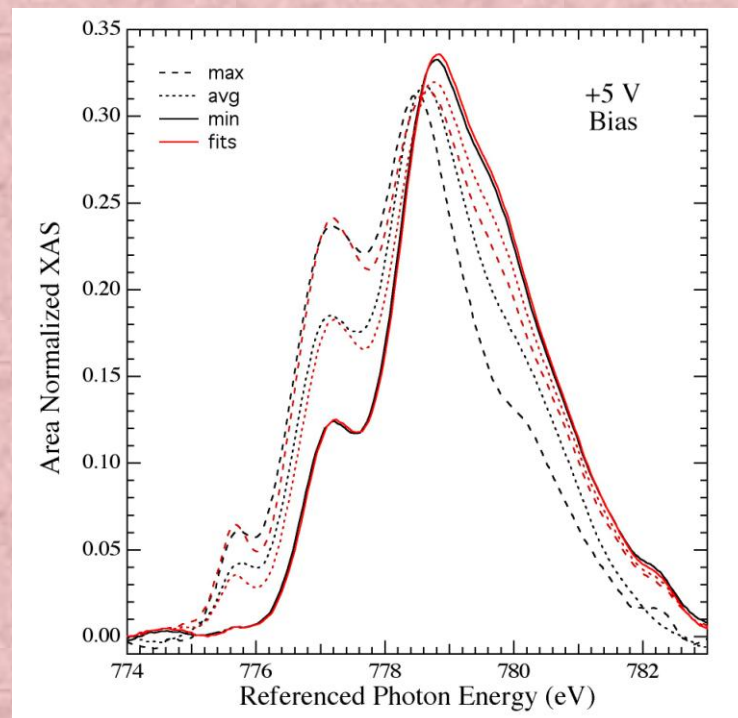


Co valence map

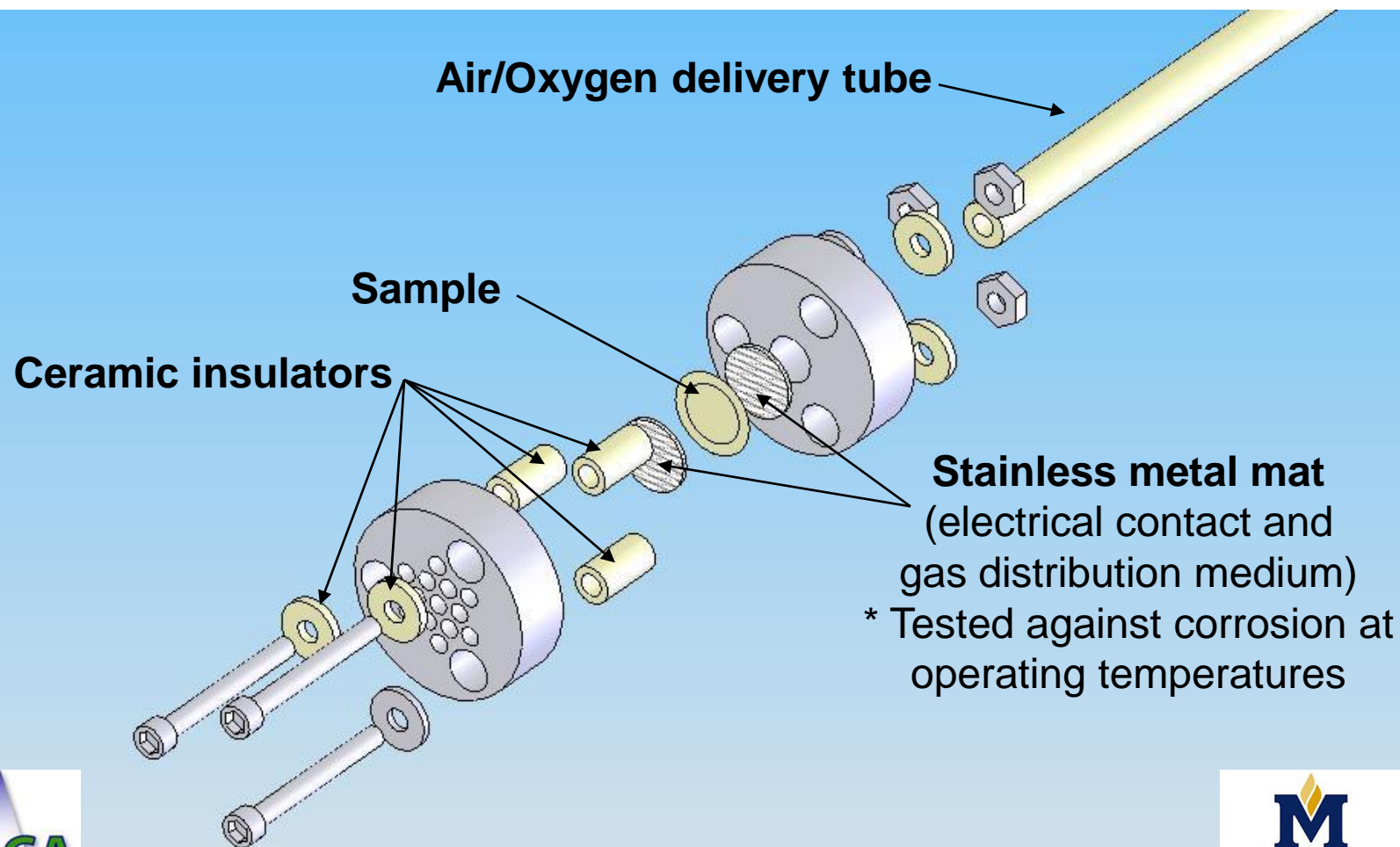


Co present as Co²⁺ and Co³⁺
(30% variation)

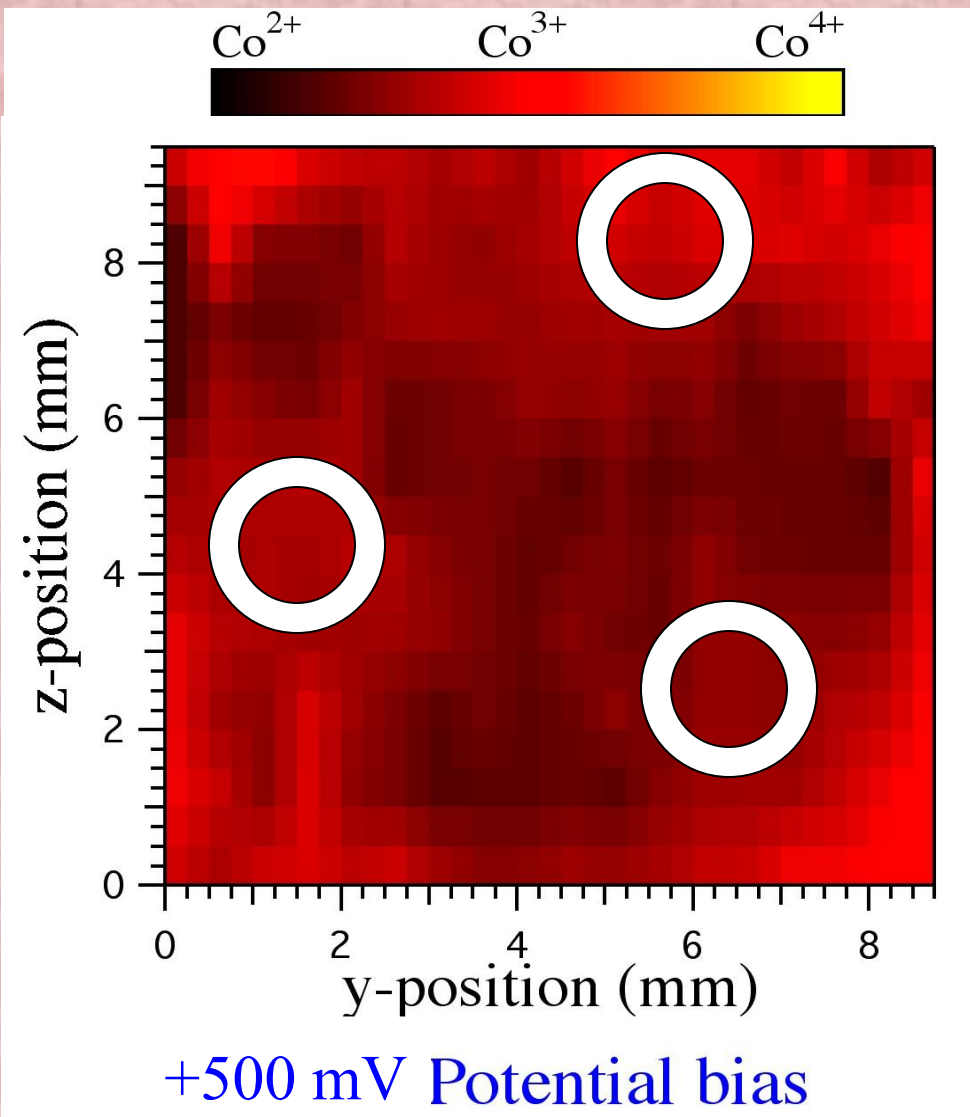
LSCF oxygen deficient
(PLD vacuum cool down)



New Testing Rig Design



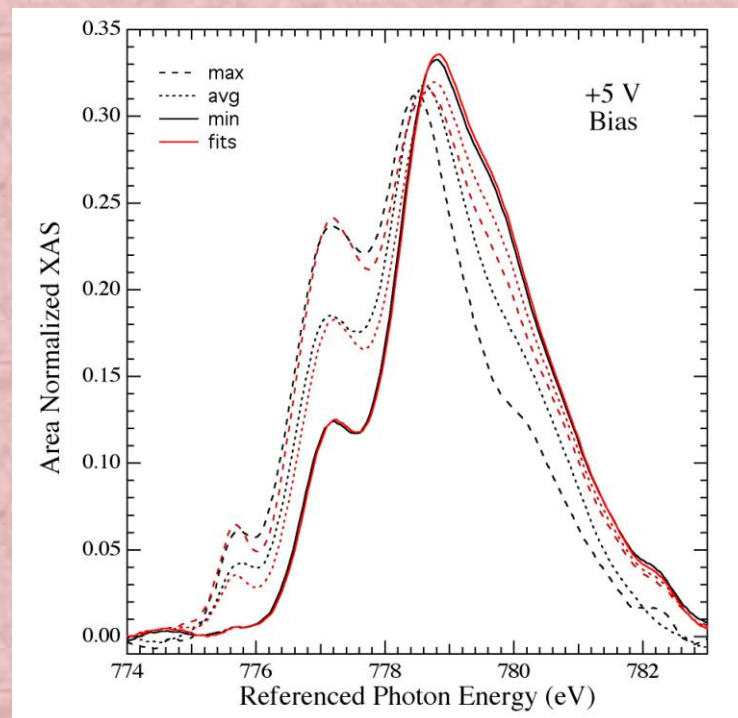
Co valence map



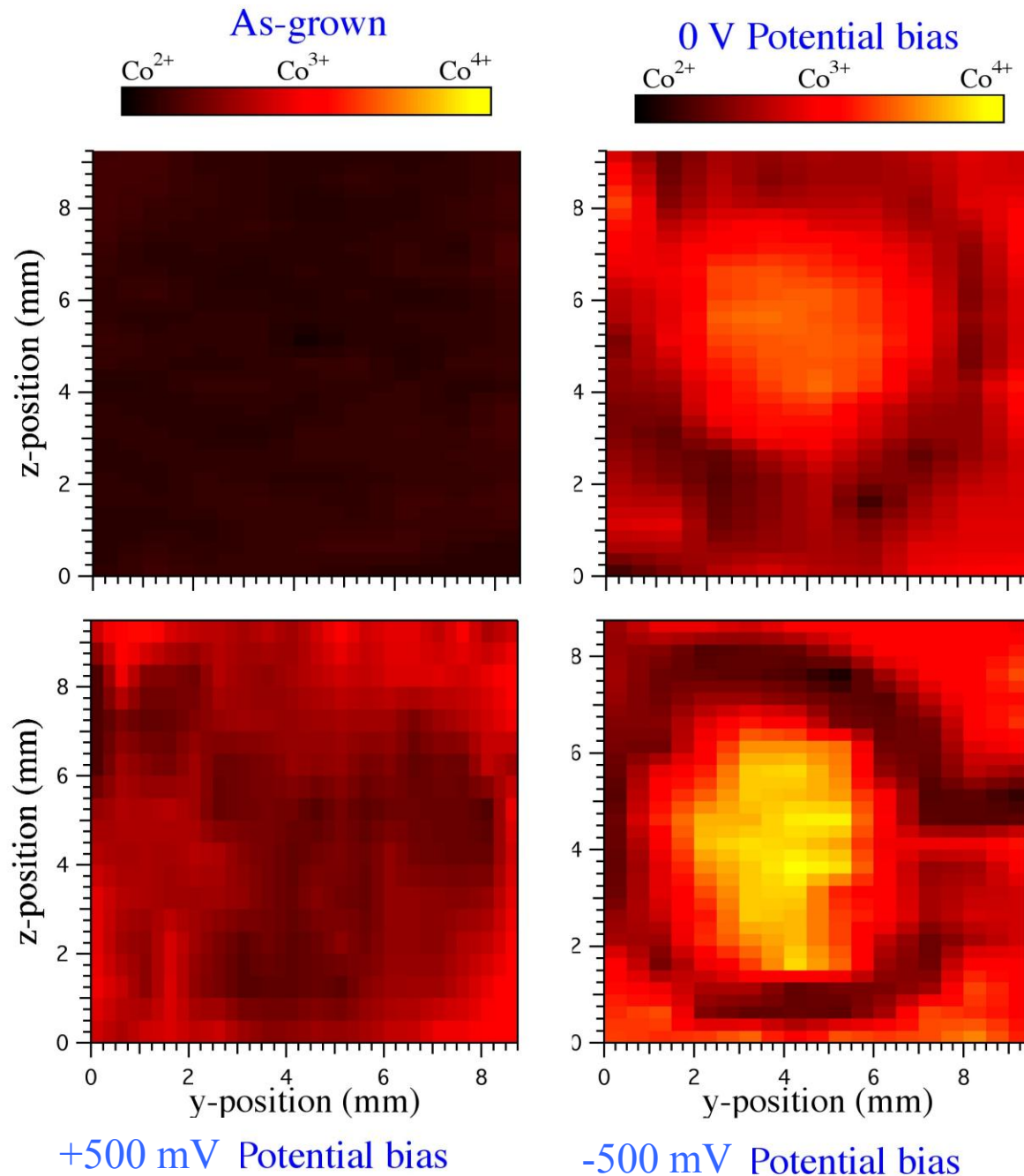
Co present as Co^{3+}
(30% variation)

LSCF oxygen deficient
(PLD vacuum cool down)

Matches air inlet



Co Valence variation LSCF/GDC/YSZ

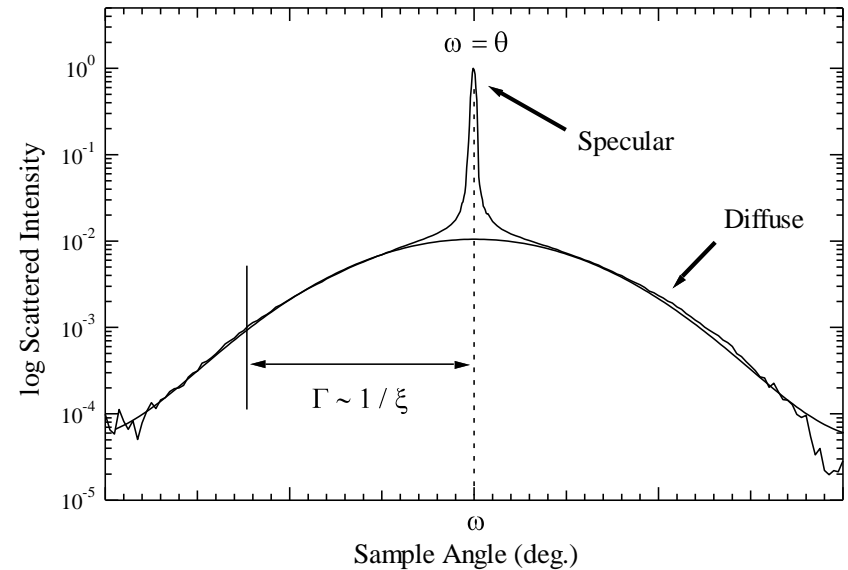
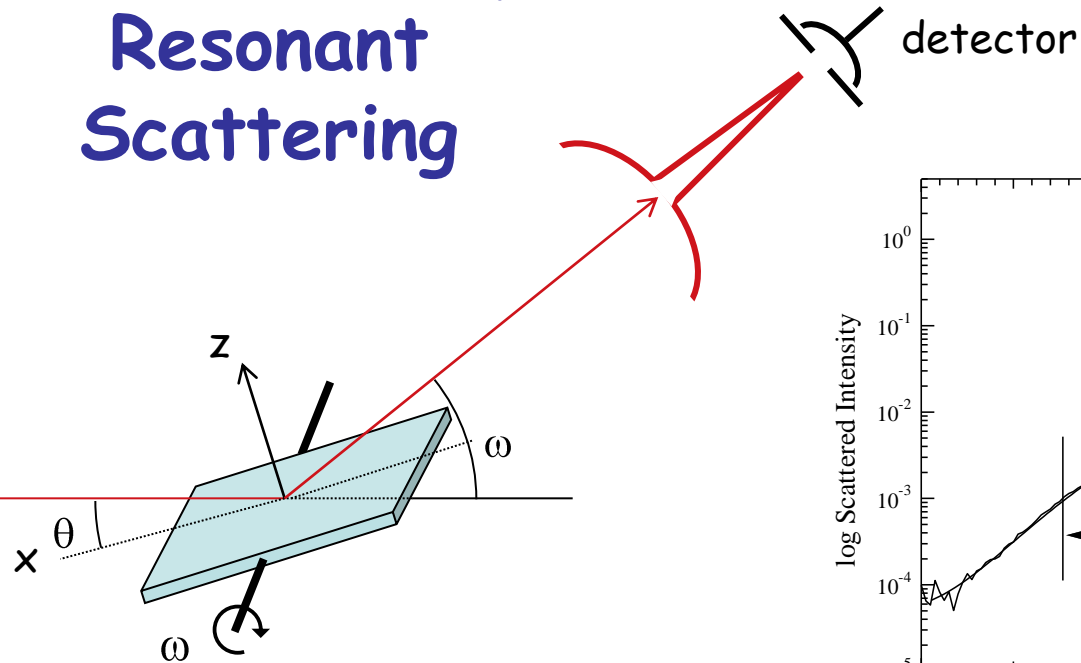


Co valence mapping

This type of mapping cannot be done at any other facility

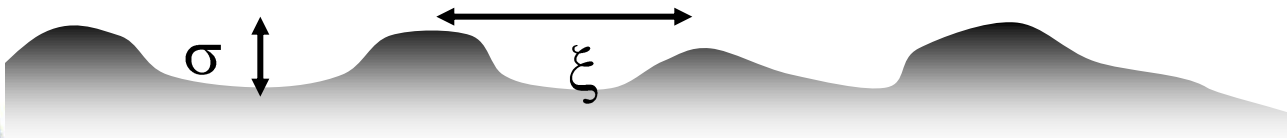
Requires full XAS scans performed in 1-3 minutes
(not 15-30 minutes)

Diffuse X-ray Resonant Scattering



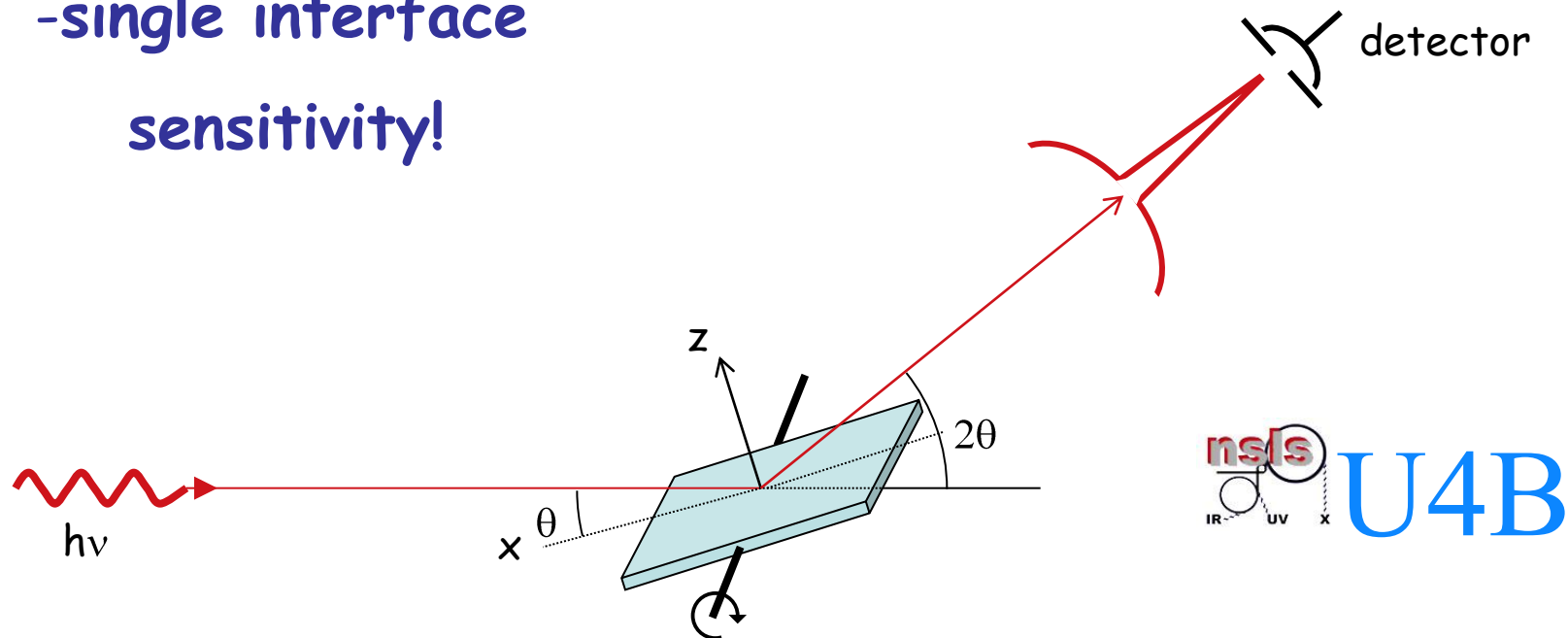
Specular vs. Diffuse Int. \rightarrow Perp. Roughness (σ)

Width of Diffuse \rightarrow In-plane Corr. Length (ξ)



Soft x-rays scattering

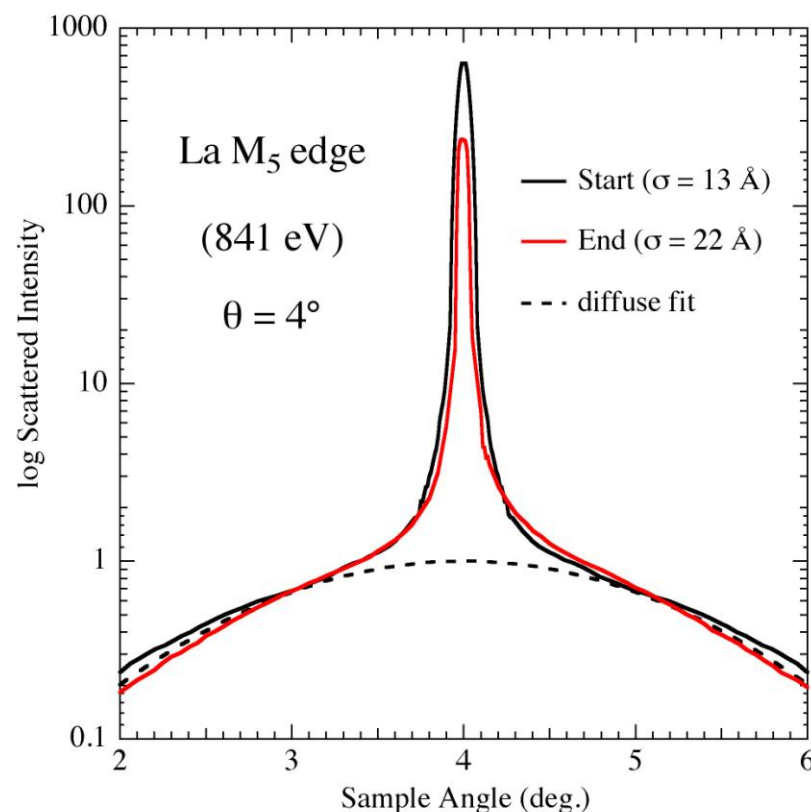
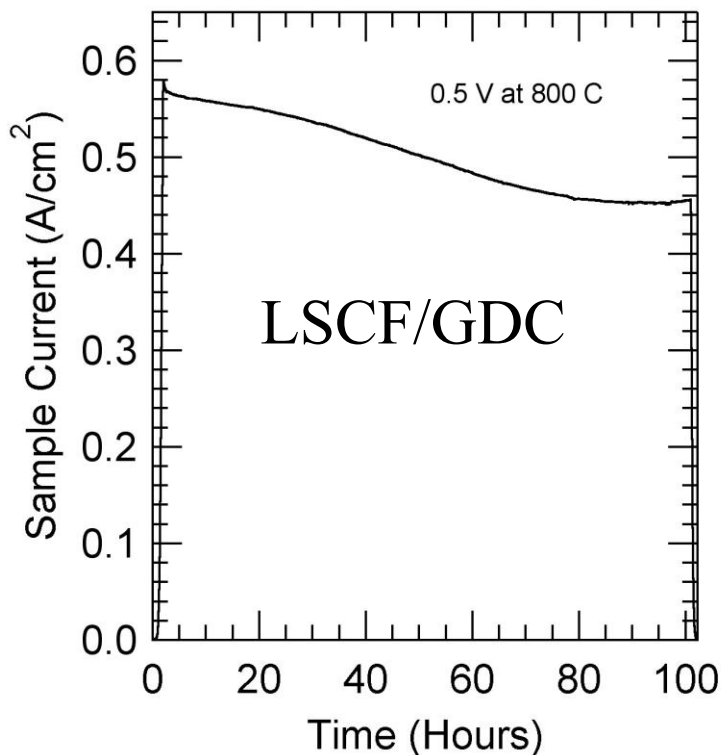
-single interface
sensitivity!



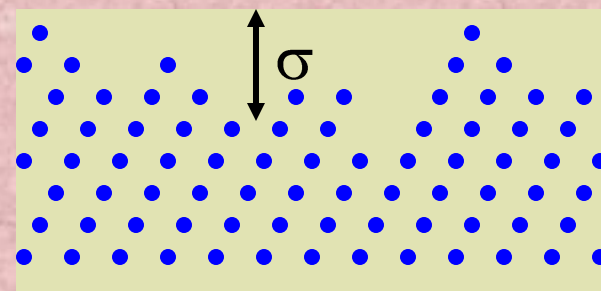
- At grazing incidence \rightarrow 15 Å penetration depth
- specular scans \rightarrow structure along z, "bulk" properties
- rocking scans (diffuse scattering) \rightarrow lateral structure
structural (chemical) roughness
in-plane roughness
perpendicular roughness



Oxygen ion flow - cation diffusion



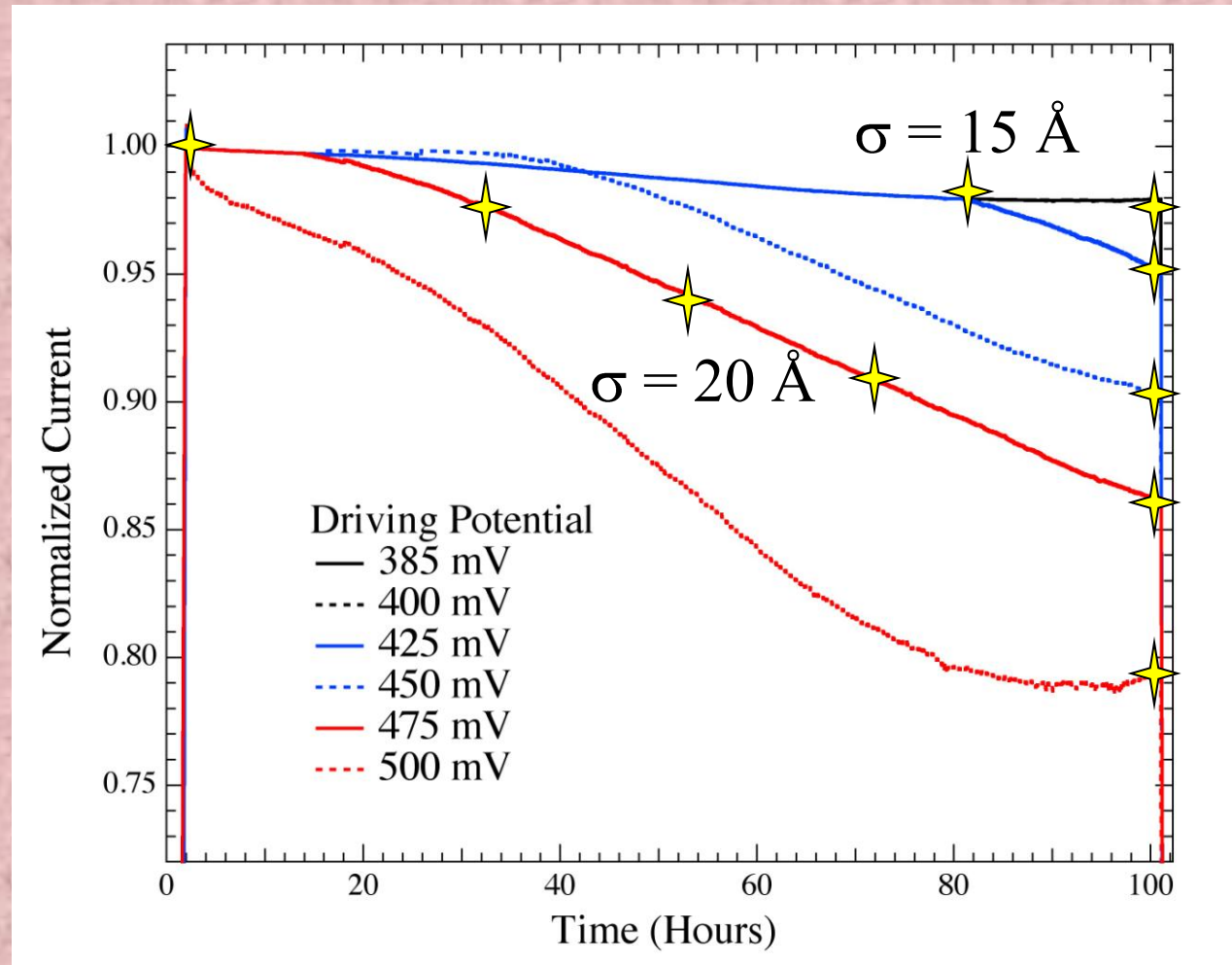
Oxygen ion flow
redistributes La at interface!
(Sr removal)



Ion flow modified interface width

Start

$\sigma = 13 \text{ \AA}$



$\sigma = 12 \text{ \AA}$

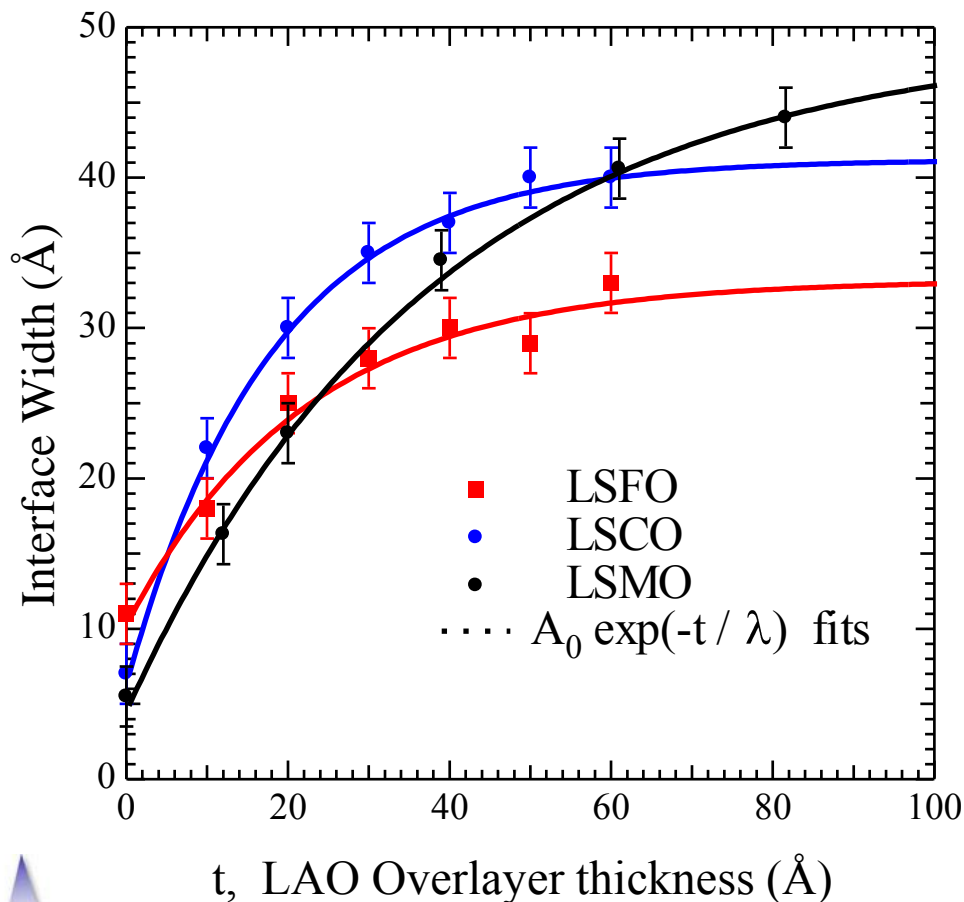
$\sigma = 18 \text{ \AA}$

$\sigma = 15 \text{ \AA}$

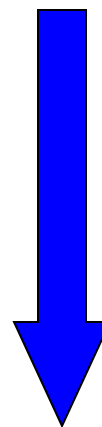
$\sigma = 20 \text{ \AA}$

$\sigma = 22 \text{ \AA}$

La Distribution in $\text{La}_{2/3}\text{Sr}_{1/3}\text{TMO}_3$ from XRS diffuse scans



Increasing Mismatch



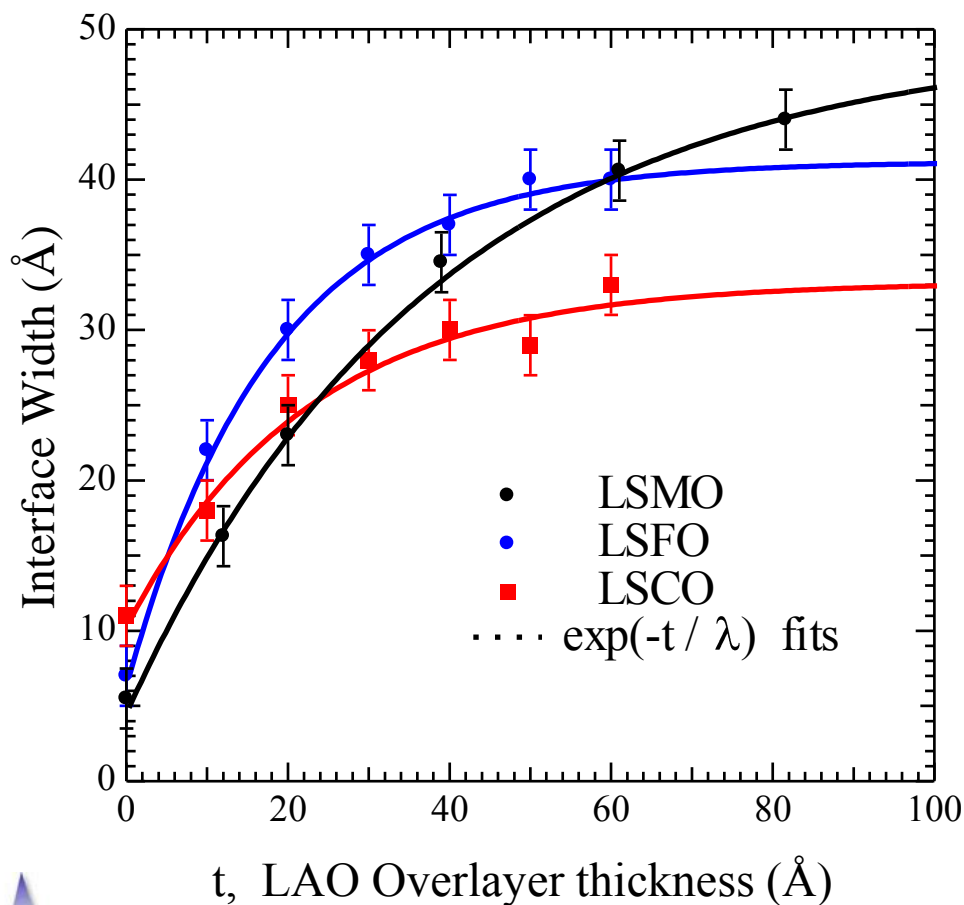
A_0 from fits

LSFO - 33.4 Å

LSCO - 41.3 Å

LSMO - 49.5 Å

La Distribution in $\text{La}_{2/3}\text{Sr}_{1/3}\text{TMO}_3$ from XRS diffuse scans



λ from fits

LSFO - 17.9 Å

LSCO - 22.2 Å

LSMO - 38.5 Å

Increasing Stiffness?



Summary

Surface potential drives Sr surface segregation

- oxygen vacancy concentration.
- Cr trace tagging does not affect Sr segregation.

Increased oxygen vacancies results in Sr out-diffusion.

- modifies Co valence (surface mapped)

Implies *in-situ* cell without oxygen partial pressure will NOT be representative of surface chemistry and electronic structure.

Future Directions

Mitigation Strategy (Sr out-diffusion)

- higher Co doping (at surface only)
- co-doping with Mn (at surface only)

Additional Dependencies

- oxygen gas flow dependence
- temperature dependence

Industrial Interactions (valence mapping)

Acknowledgements

Post-doctoral Fellow

Alex Lussier

Graduate Students

Martin Finsterbusch

Vanessa Pool

Adam McClure

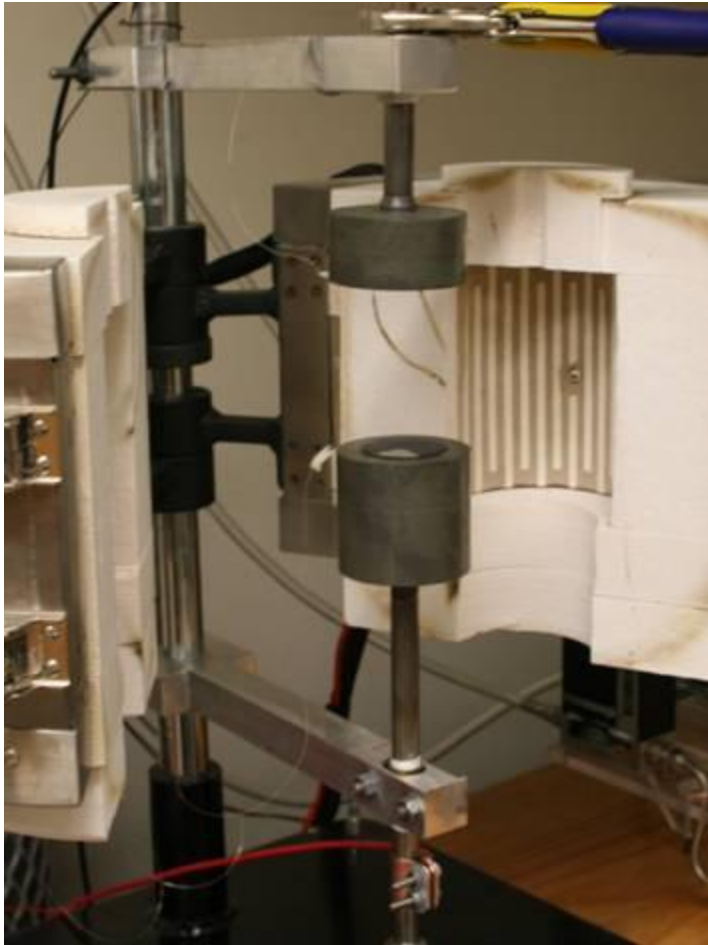
Beamline 6.3.1

Advanced Light Source (ALS)

Dr. Elke Arenholz (ALS scientist)



Testing rig(s)



- Seal-less design
- Contact paste-less tests

